

EBSD in TEM : Introduction to ASTAR system

Orientation and Phase Mapping with Transmission Electron Microscopes

Muriel Veron, Edgar Rauch, Laboratoire



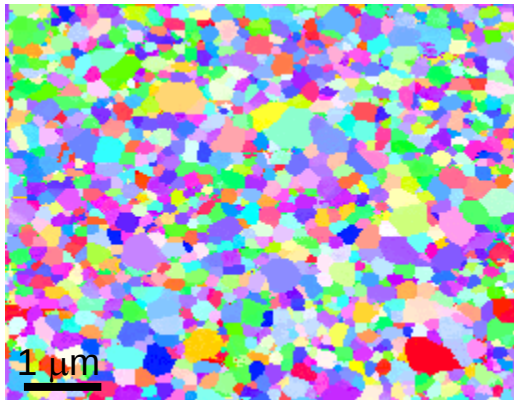
CNRS / Grenoble - INP

- *ACOM/TEM* : Automated Crystal Orientation Mapping on TEM
- '*DigiSTAR*' : Precession tool for TEM

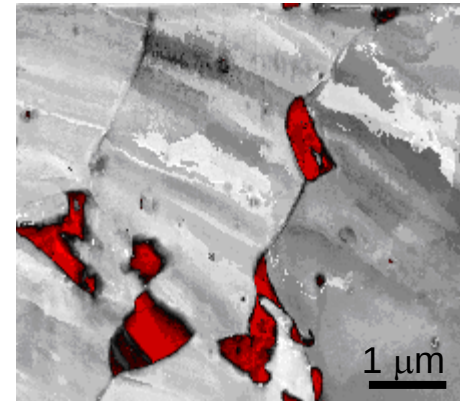


NanoMEGAS
Advanced Tools for electron diffraction

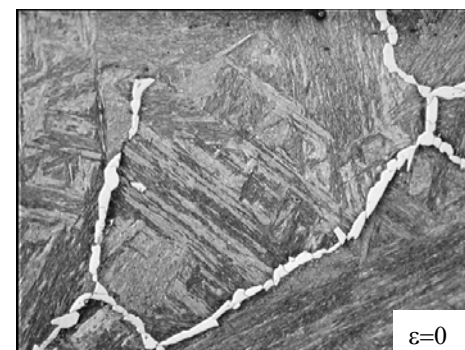
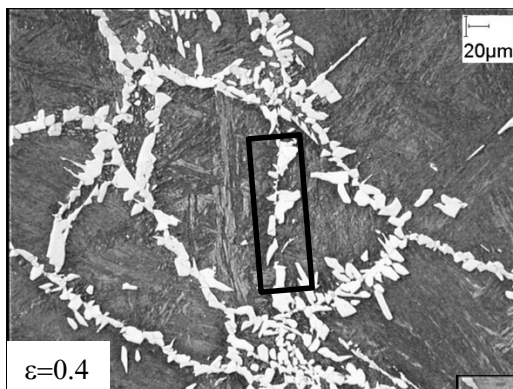
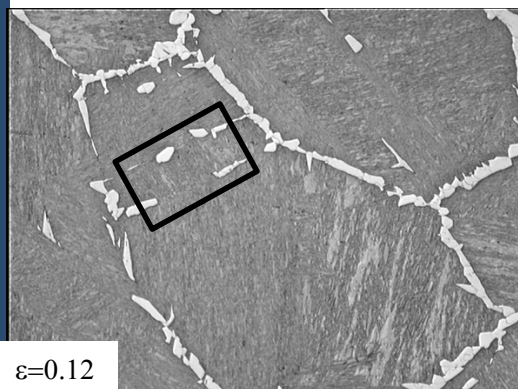
= ASTAR



Nanocrystalline Al

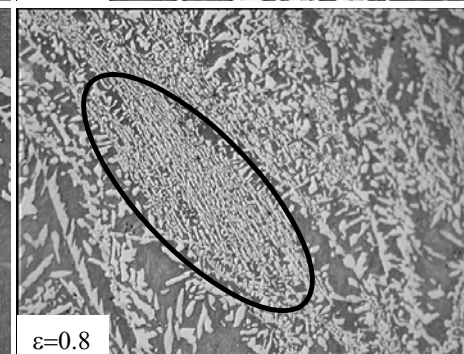
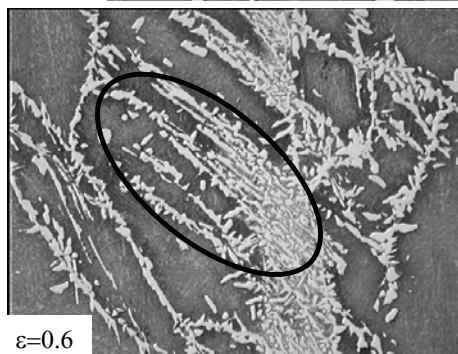
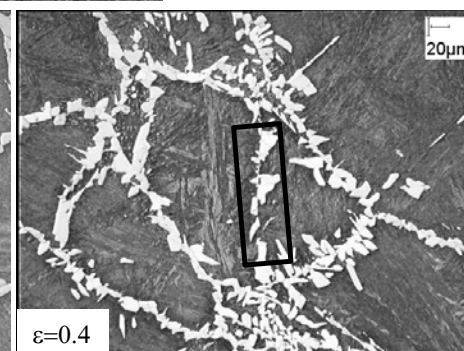
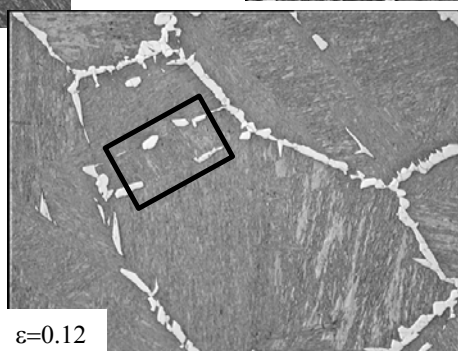
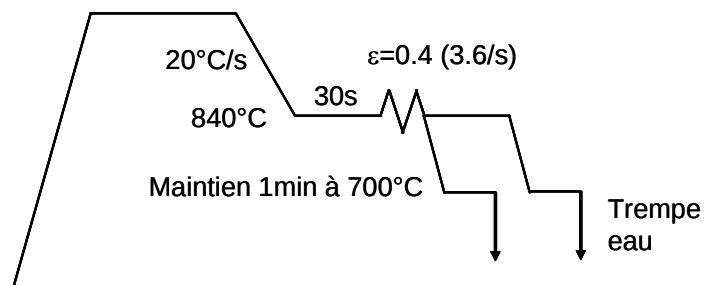


TRIP steel with retained austenite

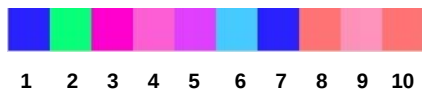


1 minute
700°C

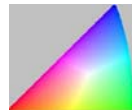
1250°C, 15min => $d\gamma=400\mu\text{m}$



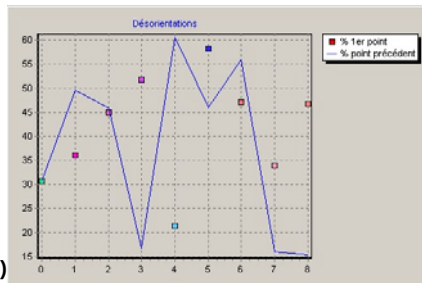
b) Points



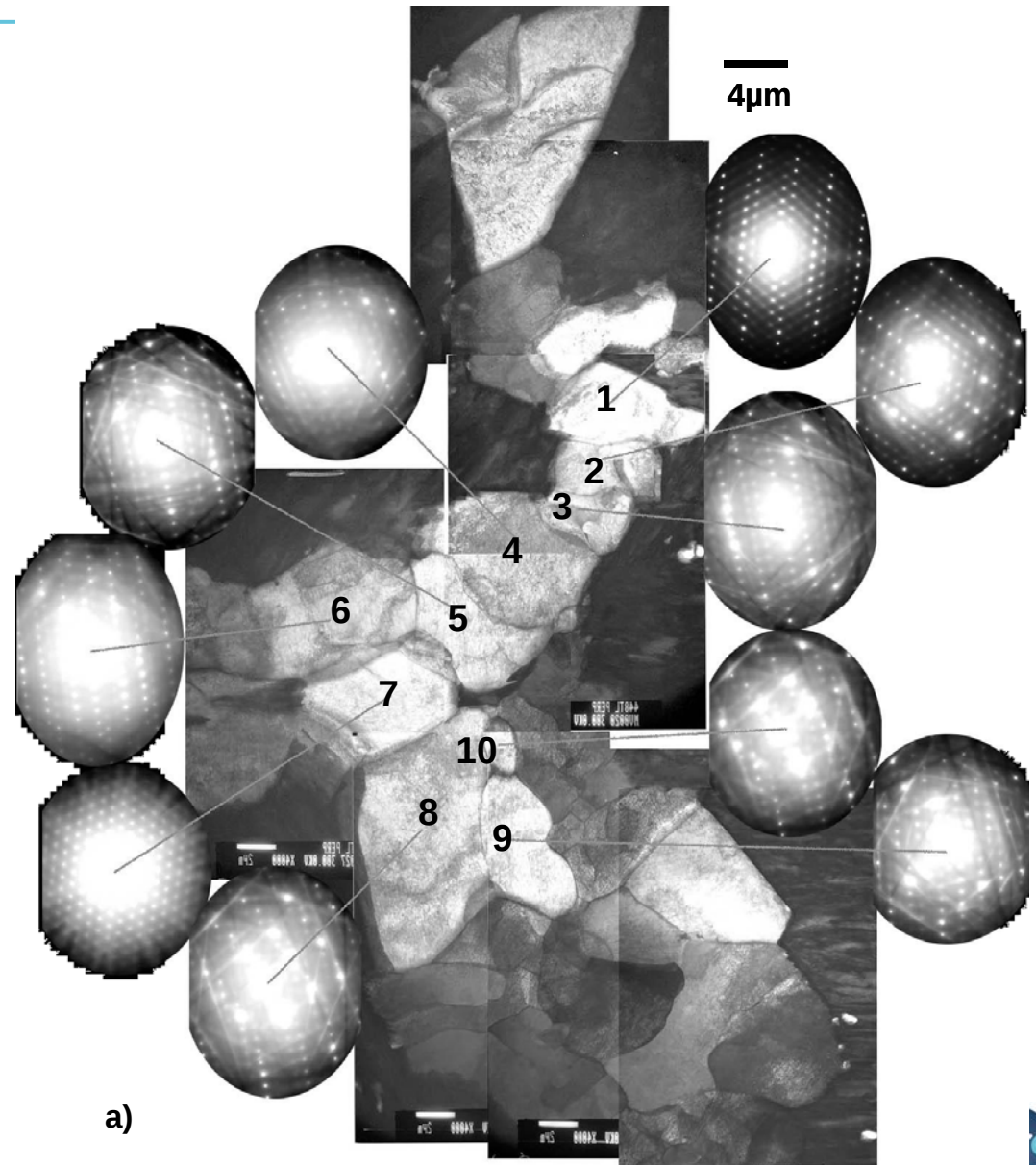
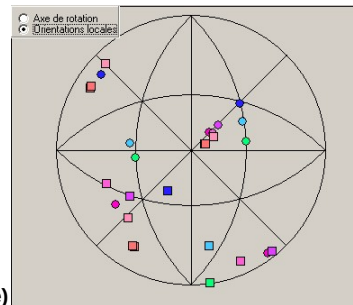
c) Code couleur



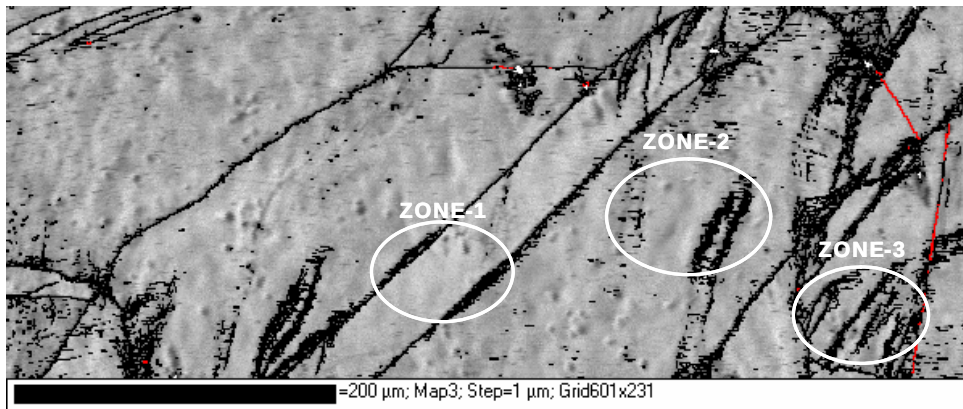
d)



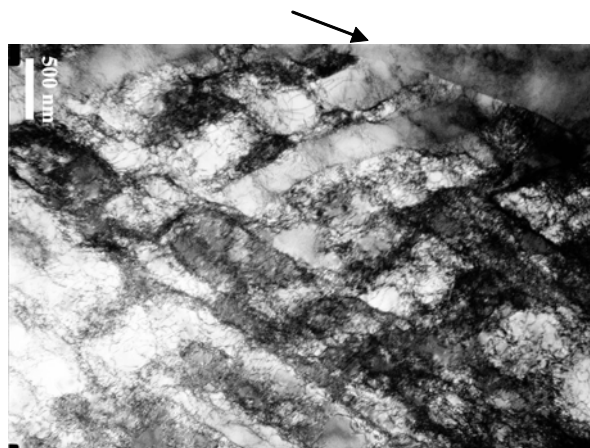
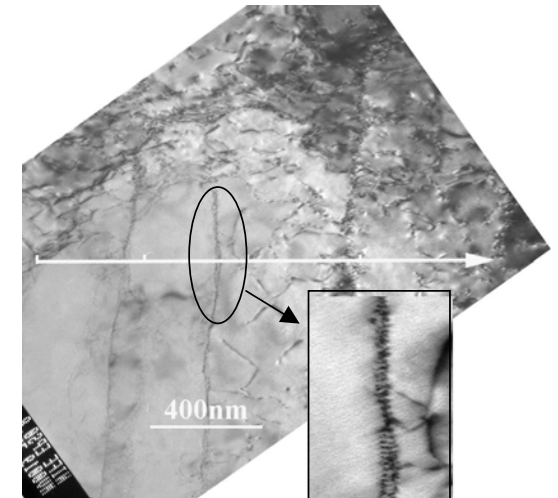
e)



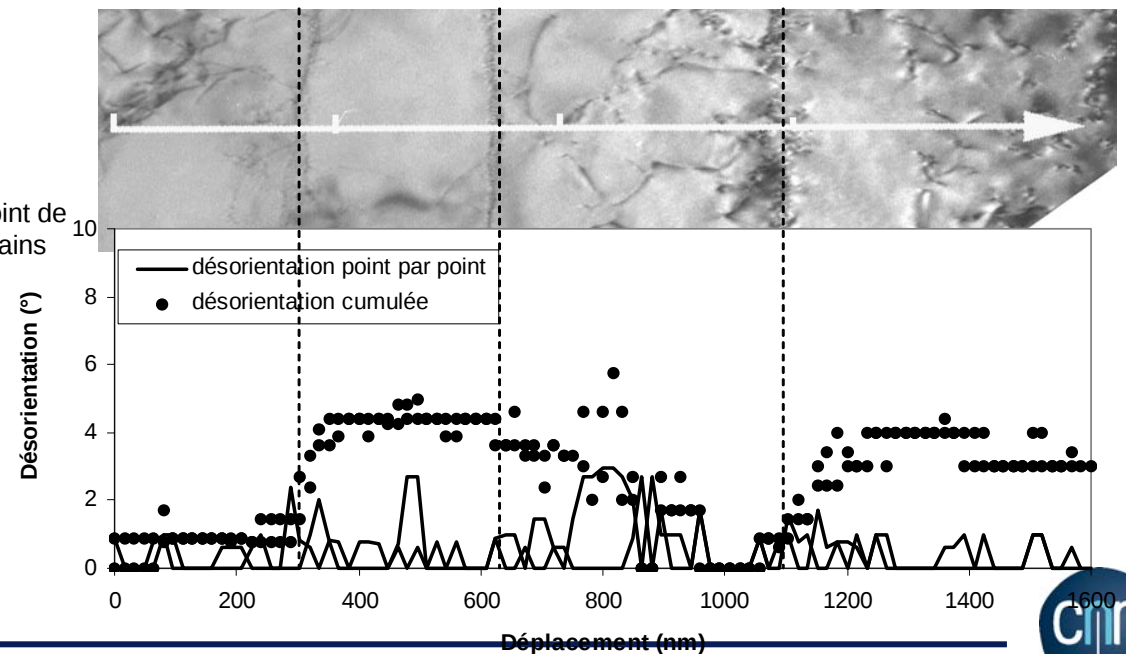
Deformed austenite (Fe-Ni alloy), EBSD quality contrast, and TEM observations



EBSD index quality contrast



Joint de grains

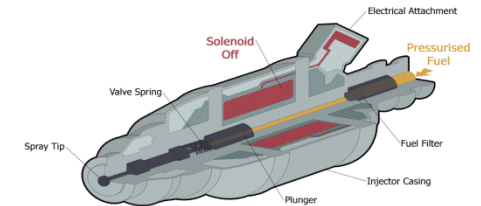


BF TEM observations

1) Example of application in metallurgy

Recrystallization of ferritic stainless steels

Collaboration with N. Meyer, Ugitech



2) ACOM/TEM

Template matching

Template generation and pattern acquisition

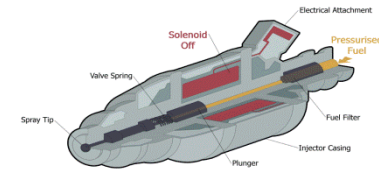
3) ASTAR

Combining orientation/phase identification
with Electron Precession

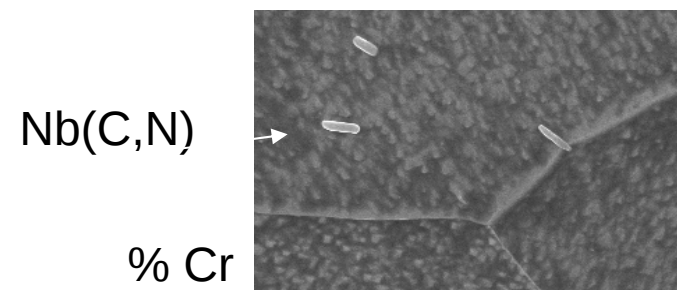
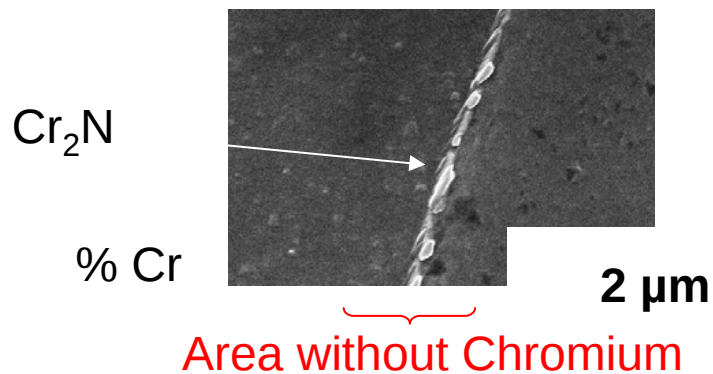
Microstructural optimization for magnetic actuators

- Alloys compositions

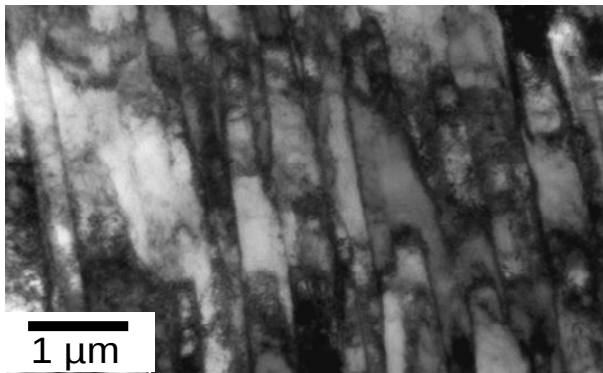
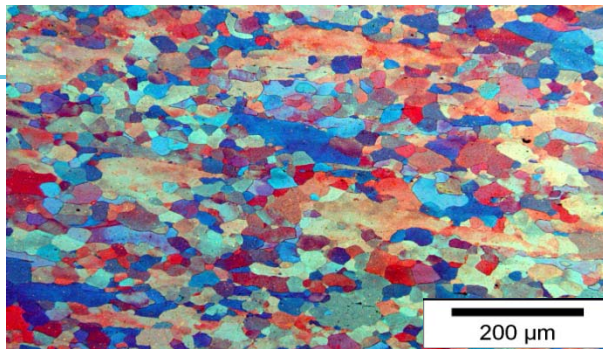
AISI	EN	C	N	Cr	Nb
430	1.4016	0.017	0.028	16.083	0.004
430Nb	1.4511	0.015	0.012	16.284	0.27



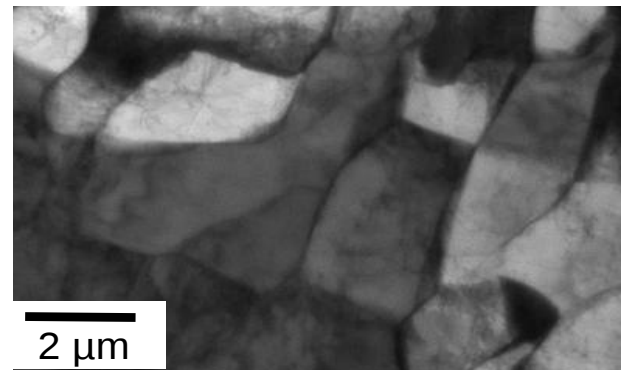
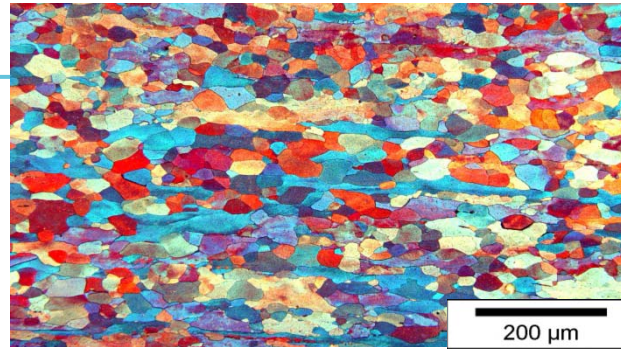
- Ferritic Stainless steel 430 ($A_1 = 880^\circ\text{C}$)
- Stabilized Ferritic stainless steel: 430Nb (ferritic at all T)



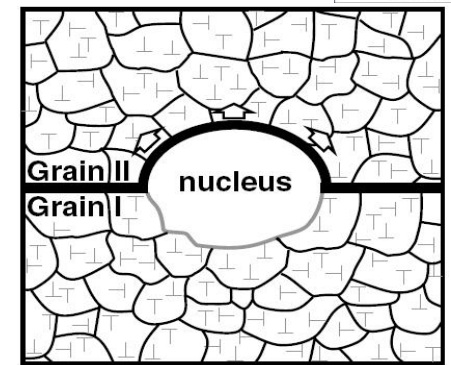
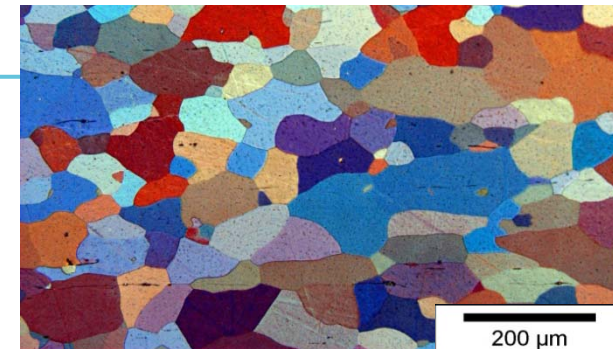
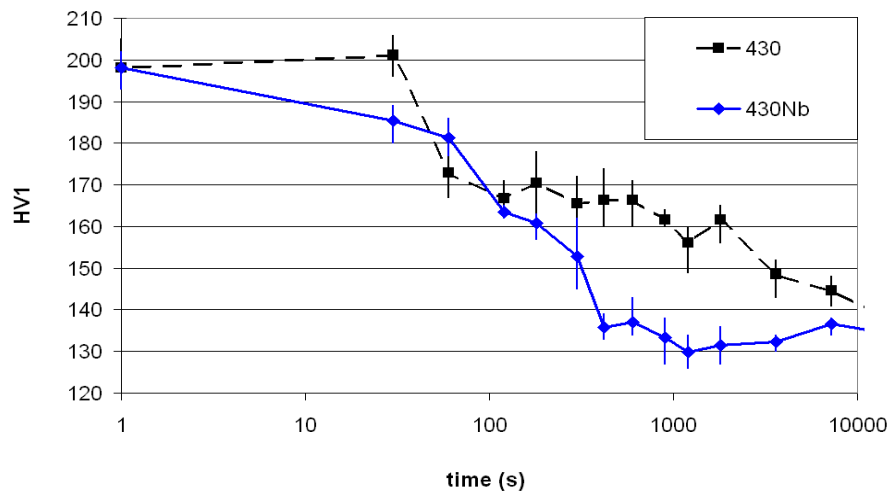
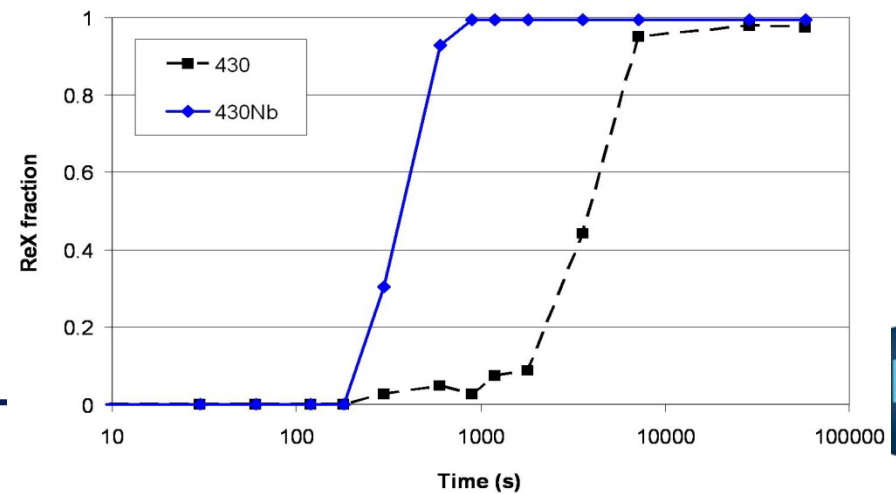
Deformed state



Static recovery



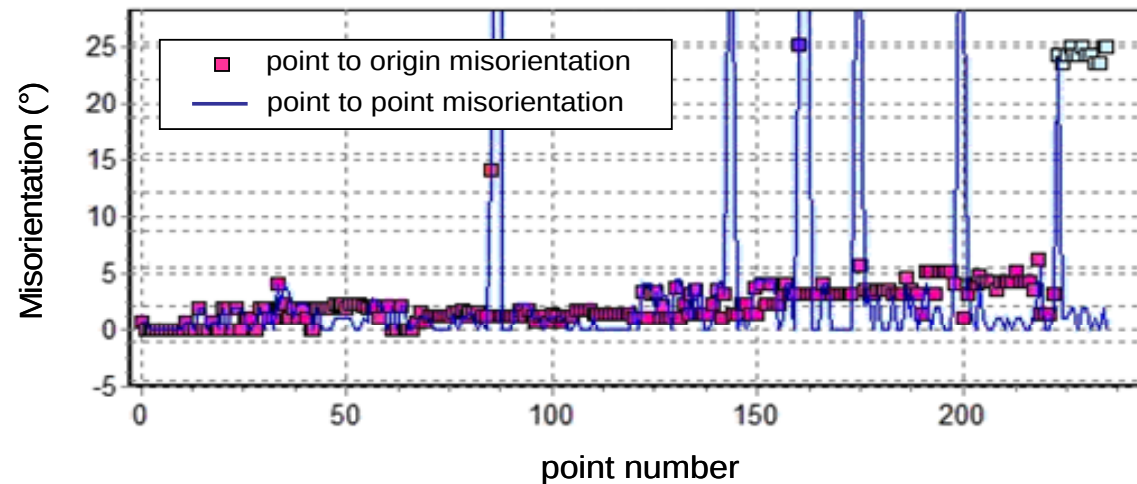
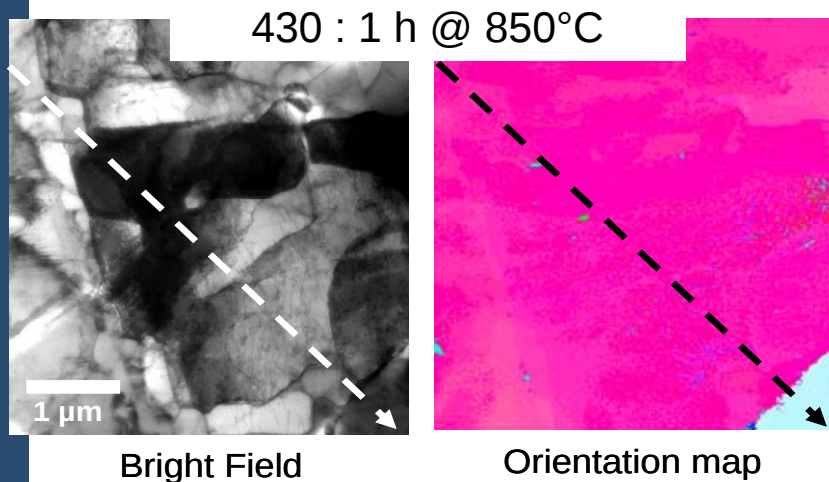
Static recrystallization

RecoveryRecrystallized fraction

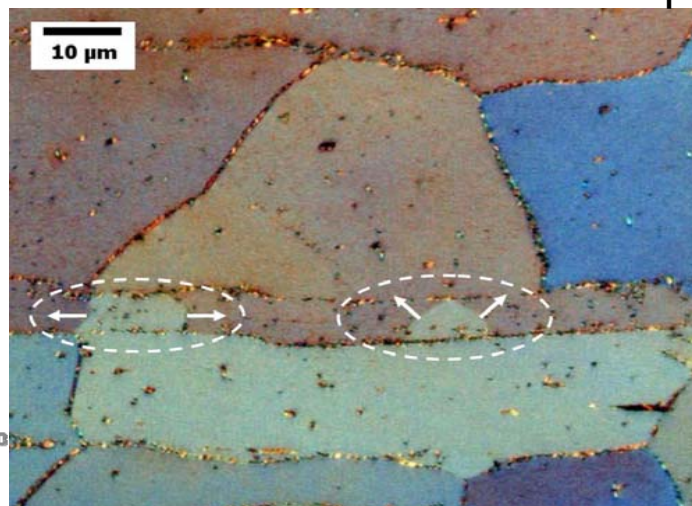
- Recrystallization mechanism

- Nucleation

- We did not observed large misorientation, even in recovered area



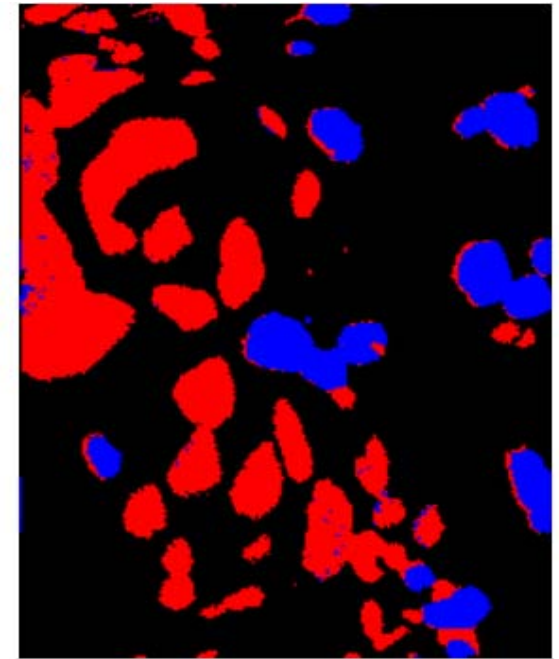
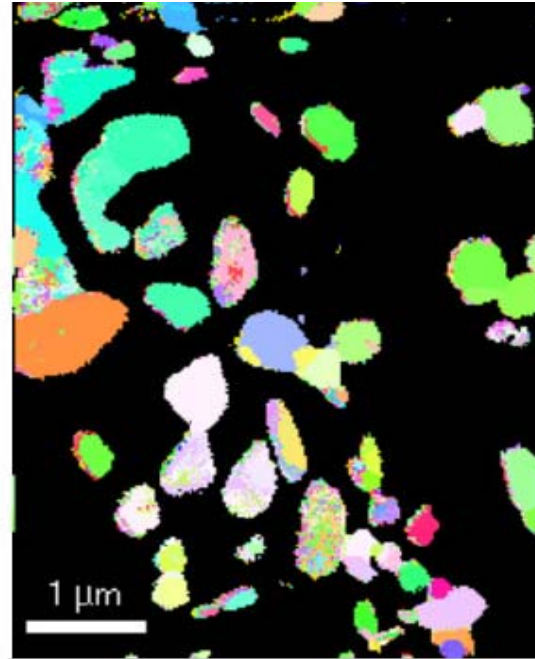
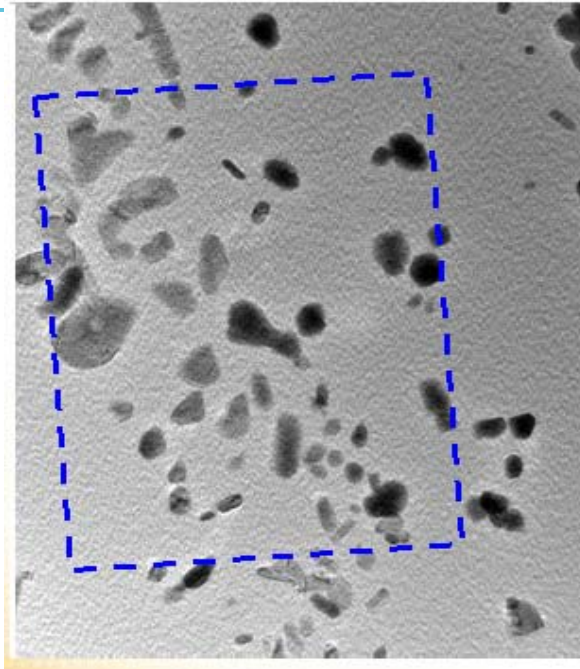
Complementary observation of bulging at GB's



430 : 7 min @ 850°C

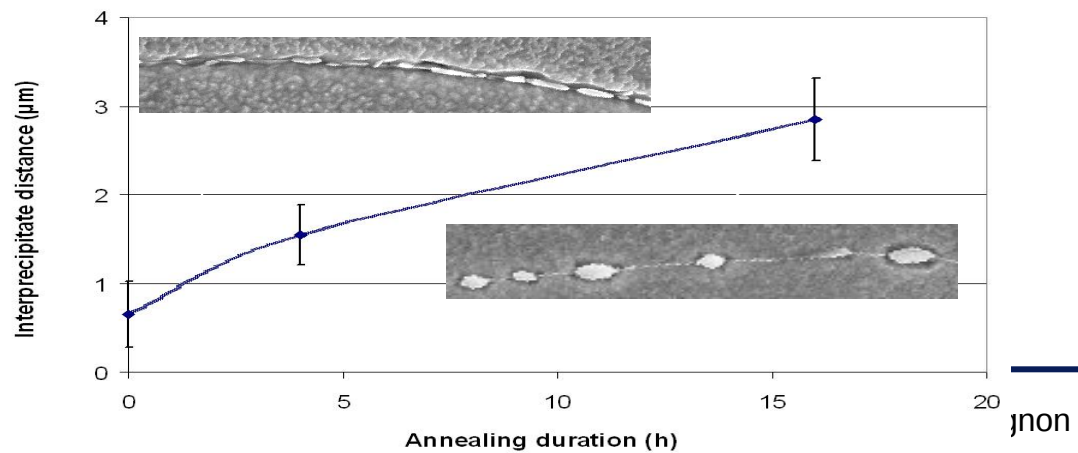
Nucleation mechanisms : SIBM, typical for low strain level

- Identification of the precipitation at the GBs (alloy 430) :

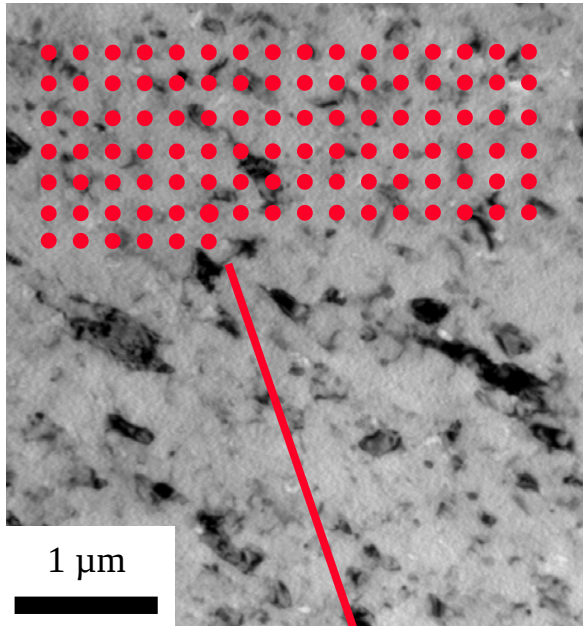


Phase identification: carbides (blue), and nitrides (red)

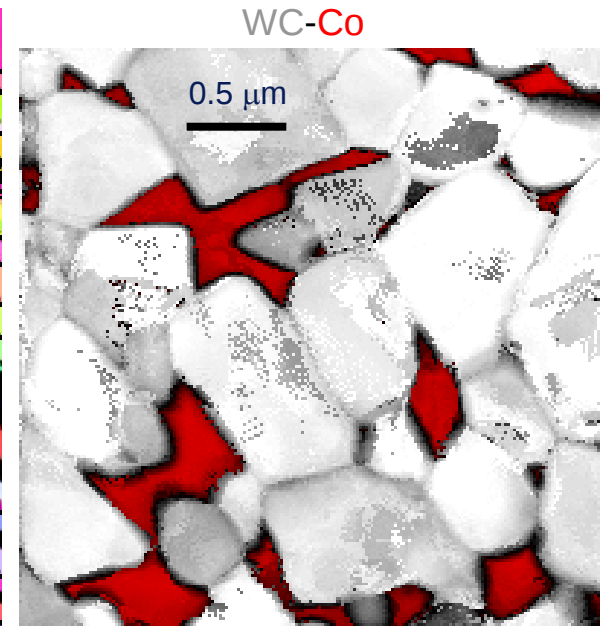
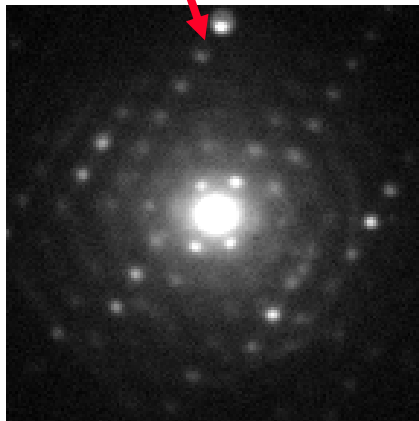
Recrystallization starts
when precipitates have
coarsened



2) ACOM/TEM : Automated Crystal Orientation Mapping

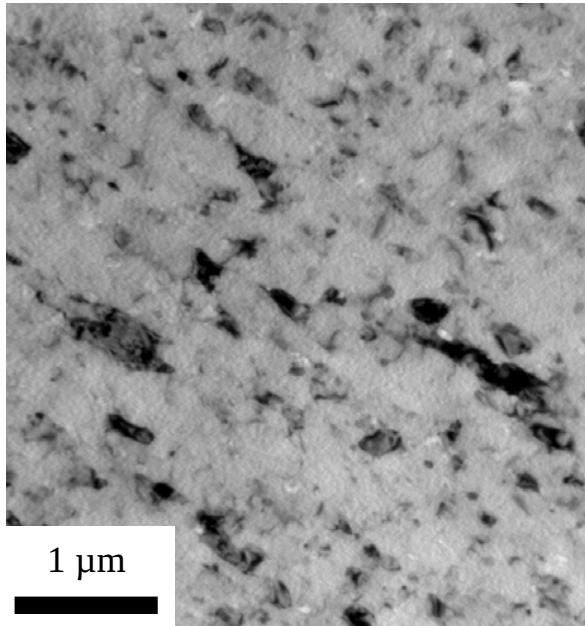


Severely
deformed
7075 Al. Alloy

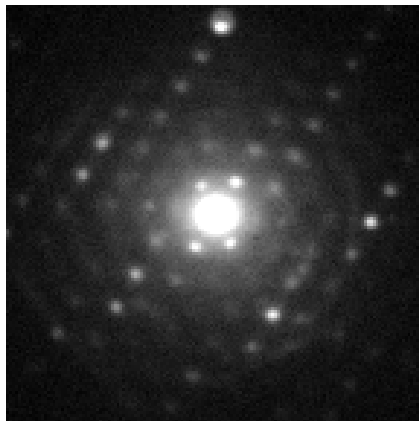


Phase map WC-Co

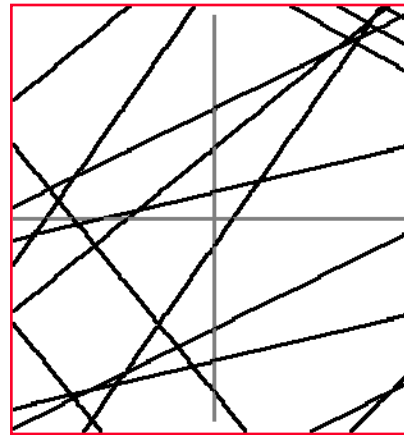
ACOM/TEM : Automated Crystal Orientation Mapping



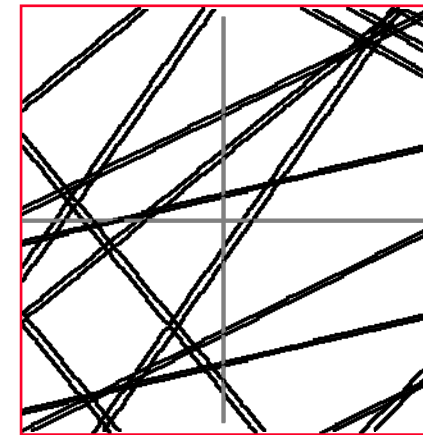
Severely
deformed
7075 Al. Alloy



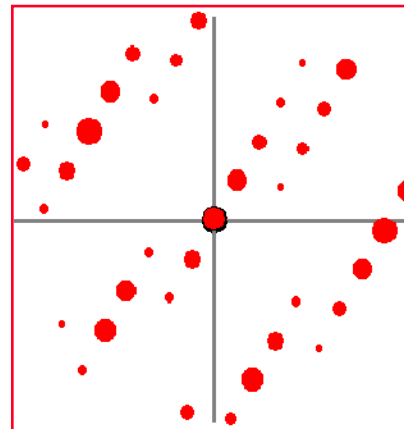
Kikuchi pattern



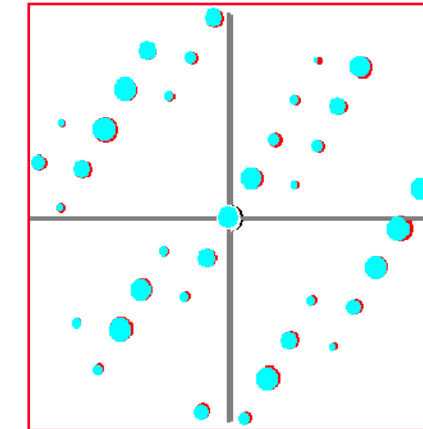
Orientation Ω



Orientation $\Omega + \Omega' (= \Omega + 0.1^\circ)$

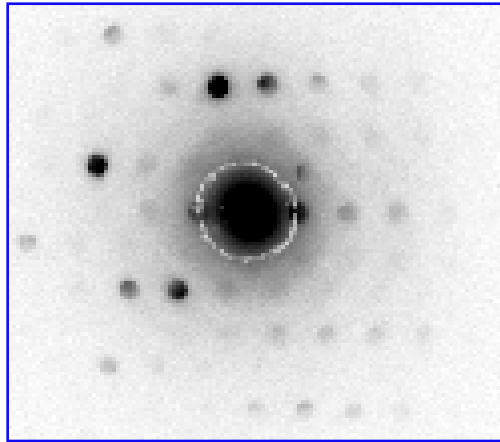


Bragg Spot pattern

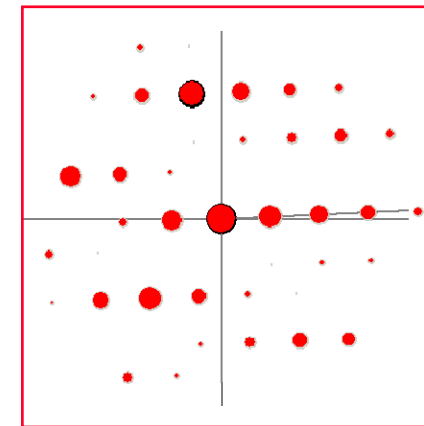


ACOM/TEM : Orientation Indexing

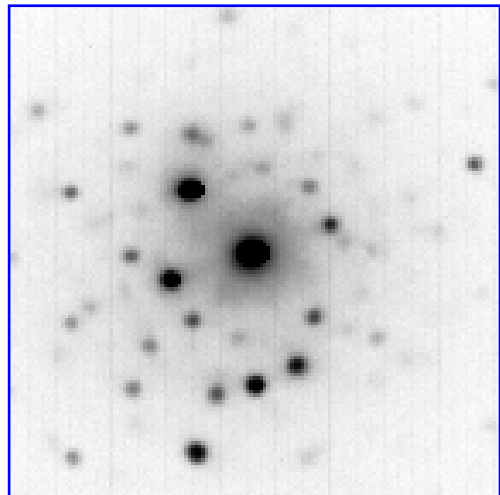
Diffraction pattern for a randomly oriented crystal



Calculated diffraction pattern



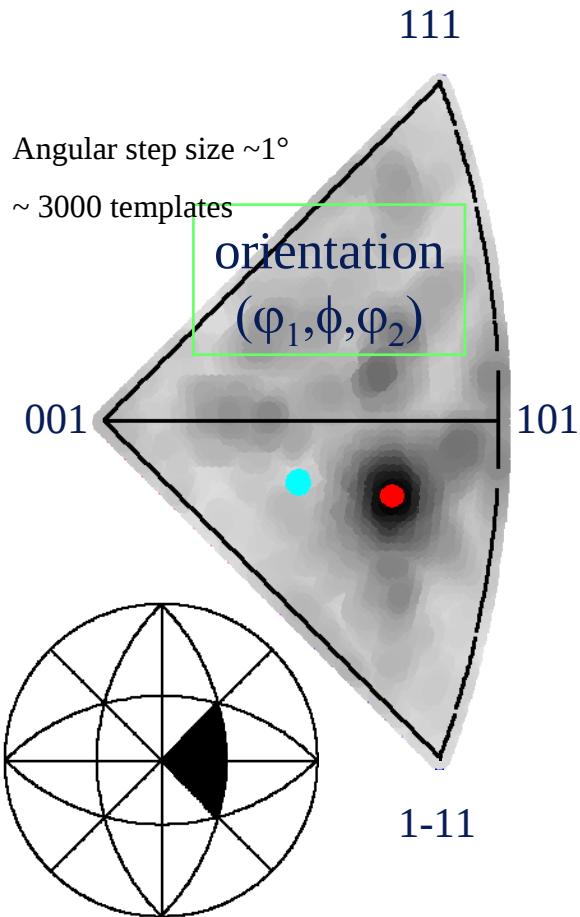
orientation
($\varphi_1, \phi, \varphi_2$)



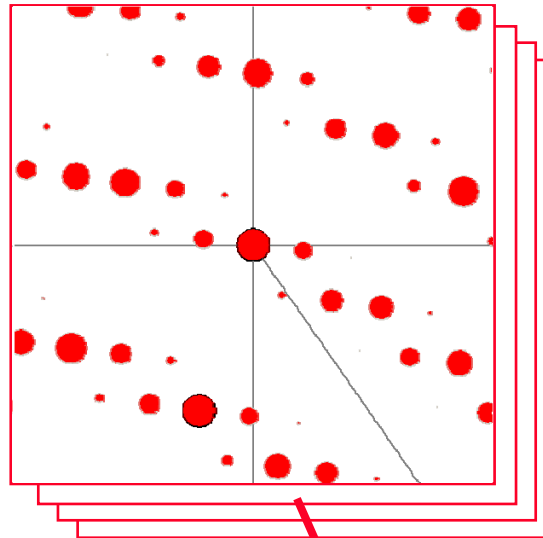
Austenite, ferrite, one or two grains?

ACOM/TEM : Crystallographic orientation identification

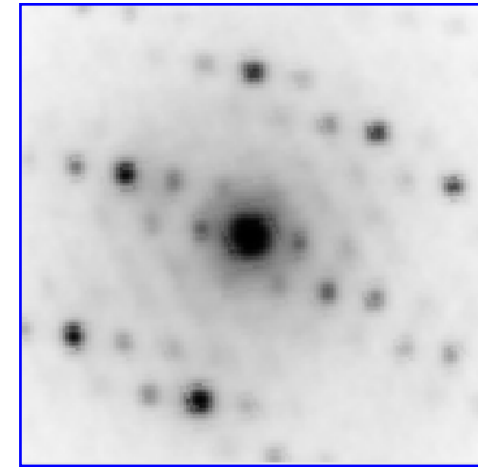
Stereographic projection (cubic)



Pre-calculated templates



Acquired pattern



$$Q(i) = \frac{\sum_{j=1}^m P(x_j, y_j) T_i(x_j, y_j)}{\sqrt{\sum_{j=1}^m P^2(x_j, y_j)} \sqrt{\sum_{j=1}^m T_i^2(x_j, y_j)}}$$

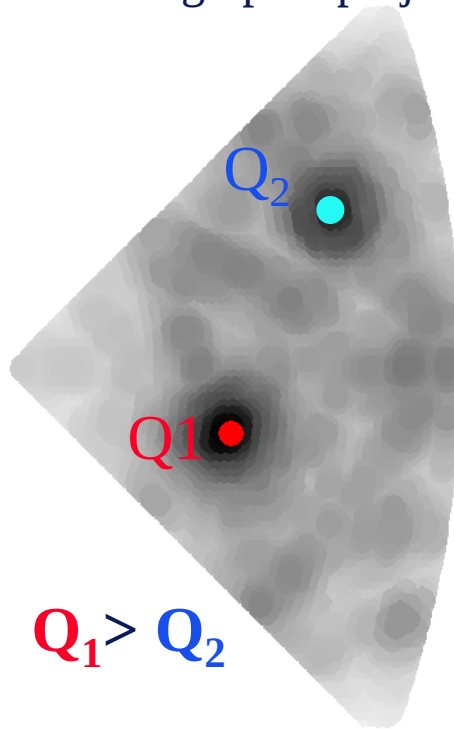
Correlation index

Template Matching

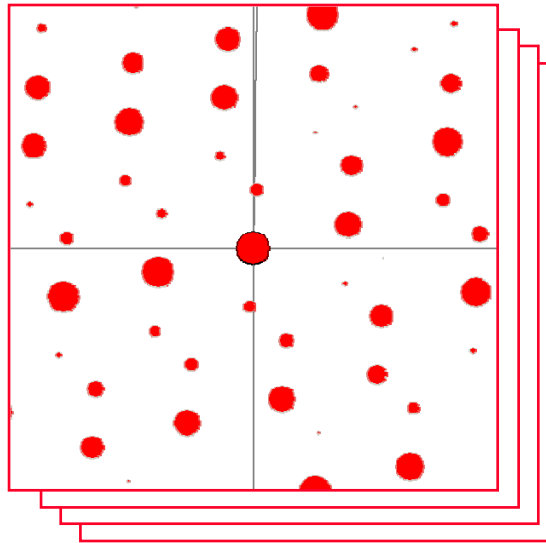
Rauch, E.F. & Dupuy, L. (2005).
 Arch. Metall. Mater. 50, 87–99.

ACOM/TEM : Reliability

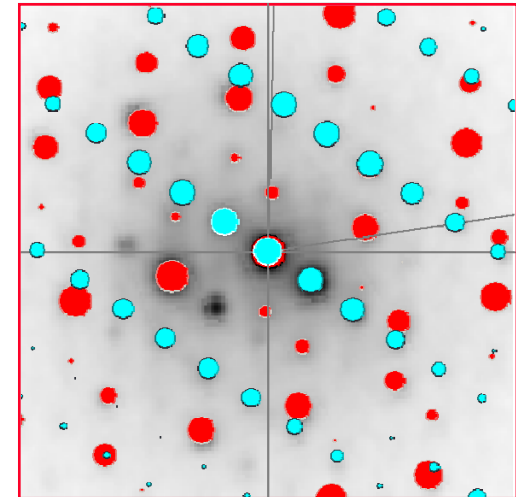
Stereographic projection



Templates for copper



Multiple Superimposed diffraction patterns at grain boundaries



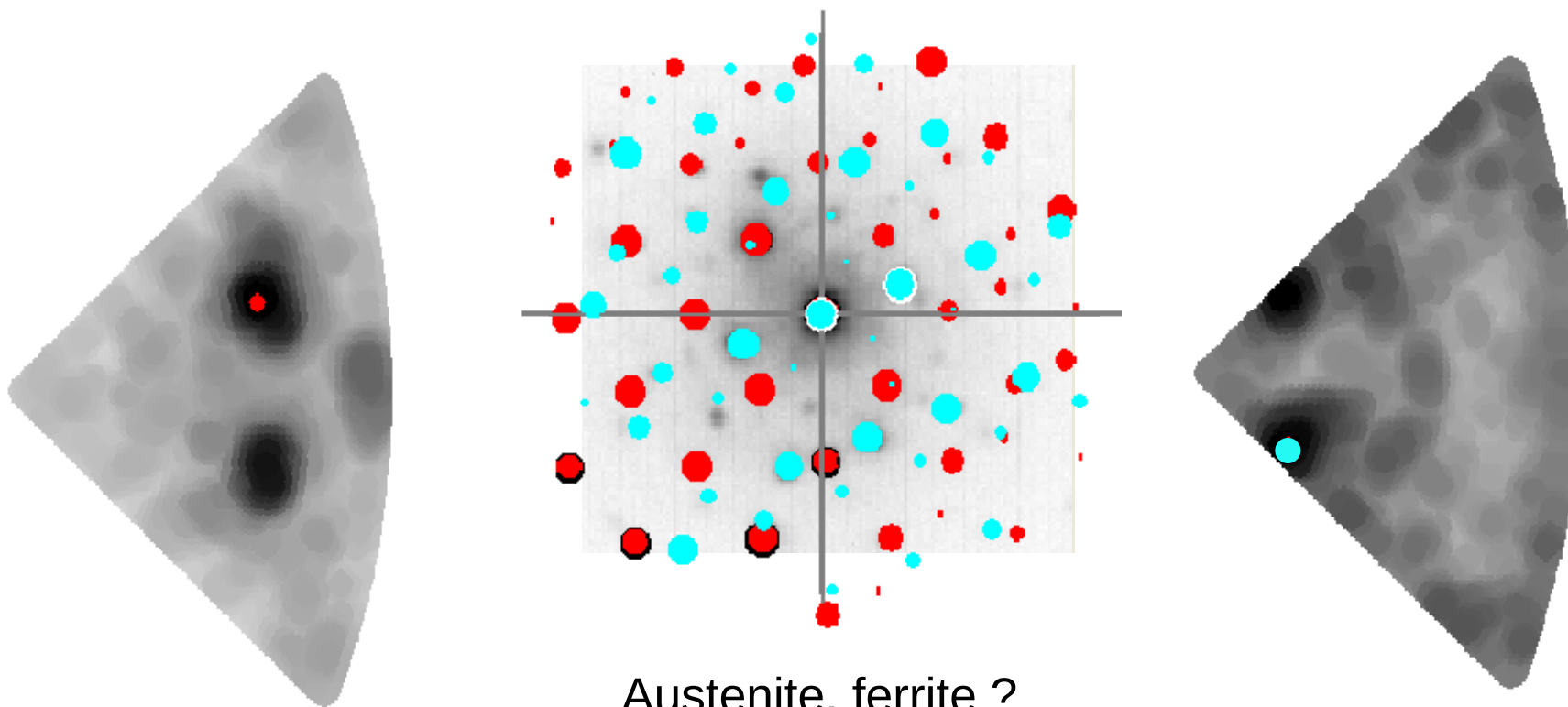
$$R = 100 (1 - Q_2/Q_1)$$

Reliability

ACOM/TEM : Phase identification and reliability

Ferrite : Index $I_1 = 553$

Austenite : Index $I_2 = 389$

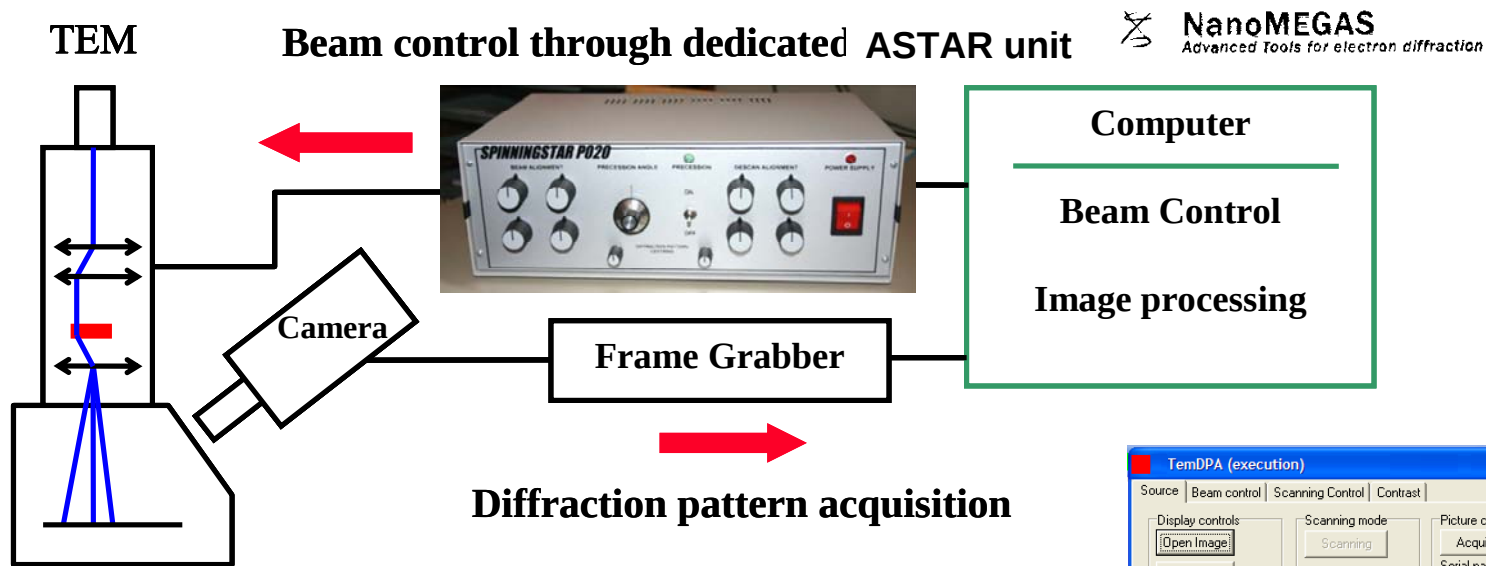


Austenite, ferrite ?

$$P_R = 100 (1 - I_2/I_1)$$

Phase reliability (= 30)

TEMdpa : Diffraction Pattern Acquisition

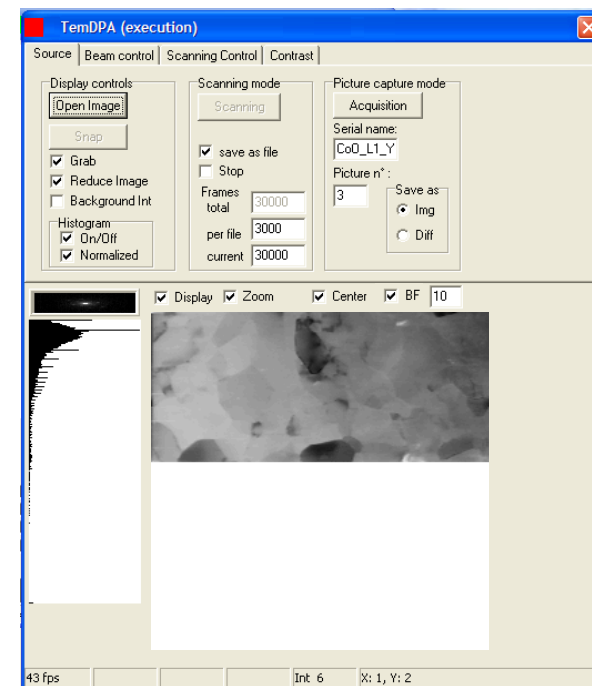


 **NanoMEGAS**
Advanced Tools for electron diffraction



Features:

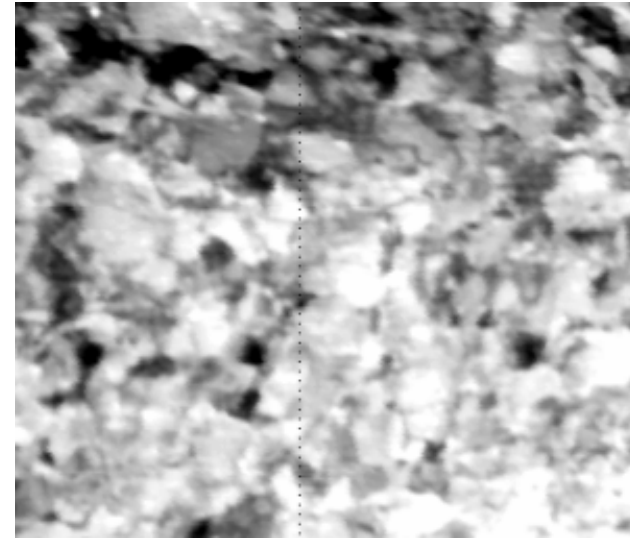
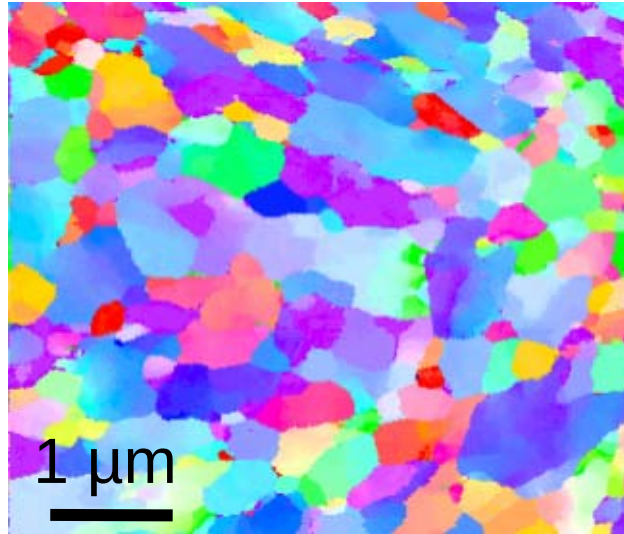
- up to 180 fps
- easy selection of the area of interest
- single or movie type DP acquisition
- brightness, contrast, exposure time control
- On line Virtual Bright Field construction



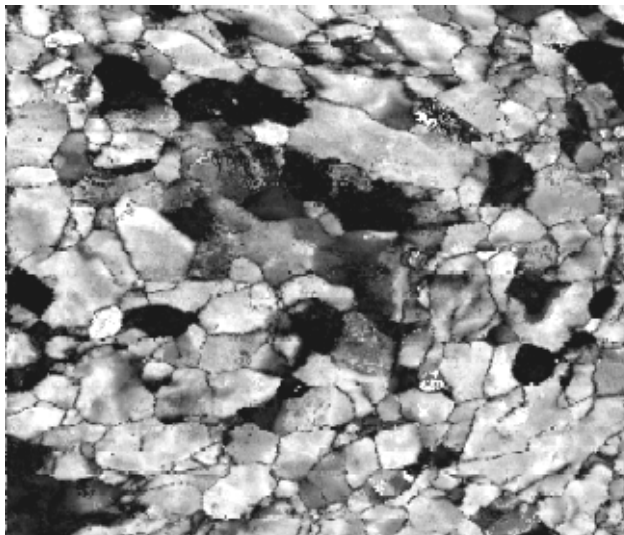
'Bright field' : Heavily deformed Cu($\epsilon=8$) (ECAP)

400x300 steps

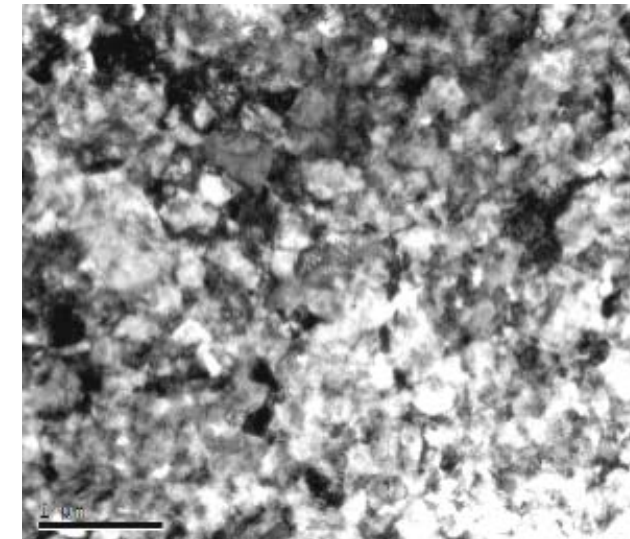
14 nm



Virtual bright field



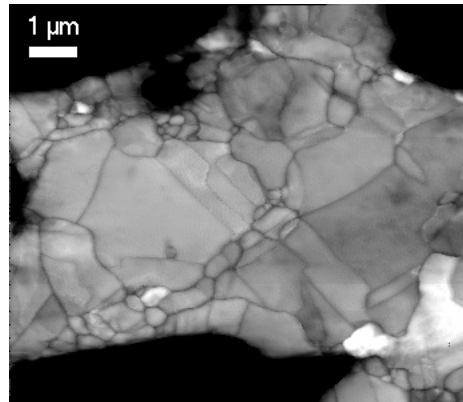
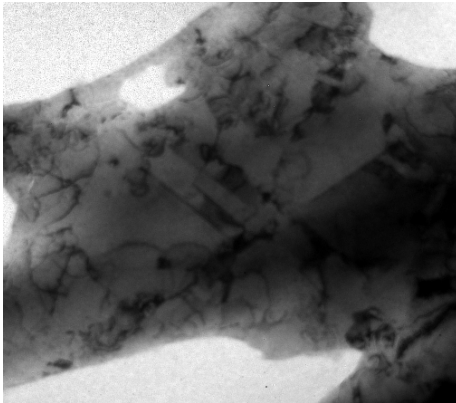
Reliability



Bright field

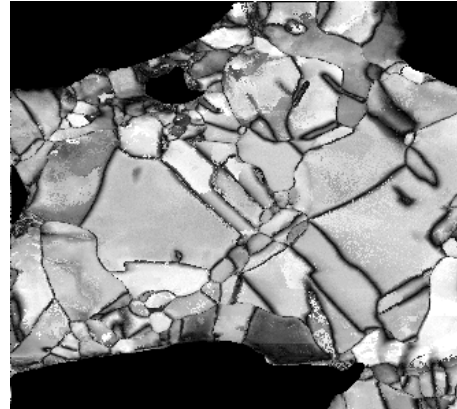
ACOM : some examples of orientation maps

Deformed Cu (coll. N. Llorca – Univ. Barcelona, Spain)

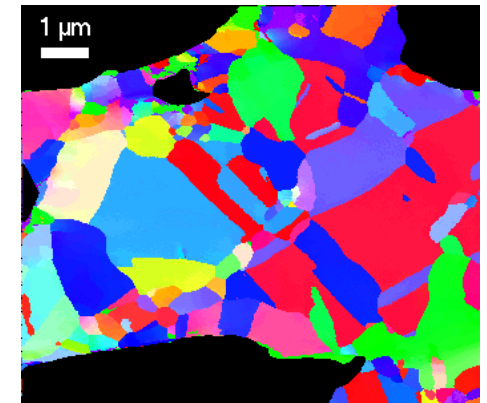


Correlation Index

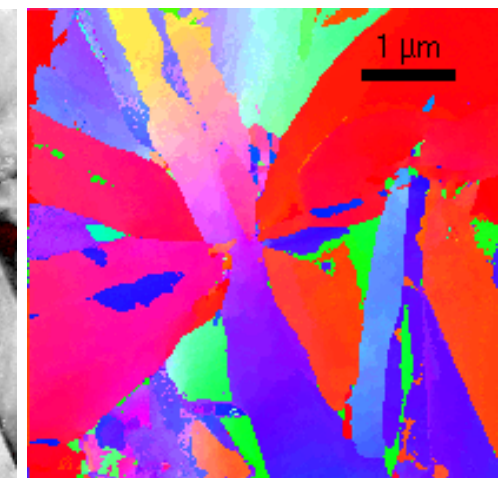
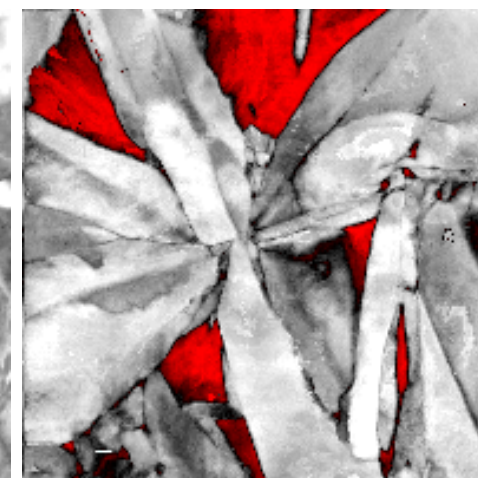
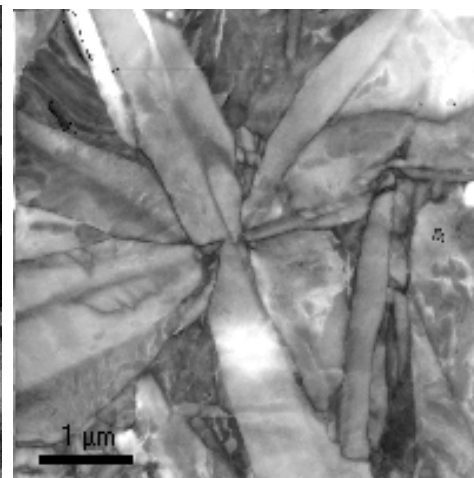
Orientation reliability



Phase Reliability



Orientations



Fe 1.67% C (HT 10 min @ 1100°C, A. Stormvinter - KTH)

Austenite Martensite

ACOM/TEM combined to a FEG-TEM

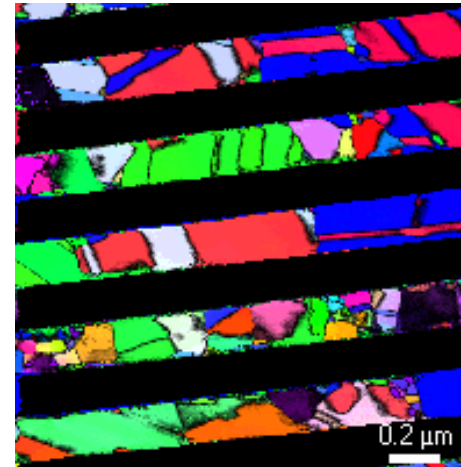
JEOL 2010F

*Texas Material Institute
UT, Austin*

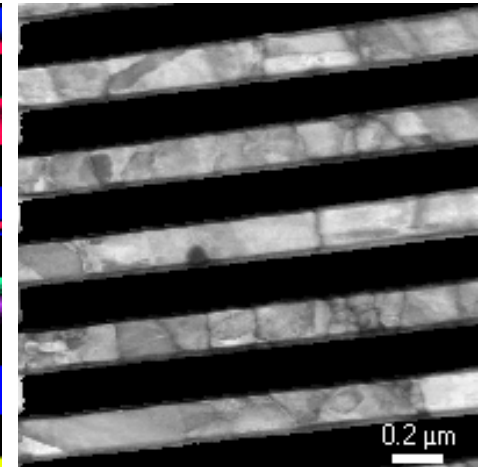
180 nm Cu lines



Virtual bright field

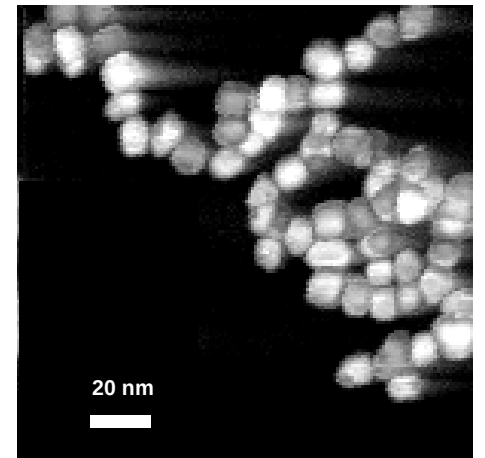
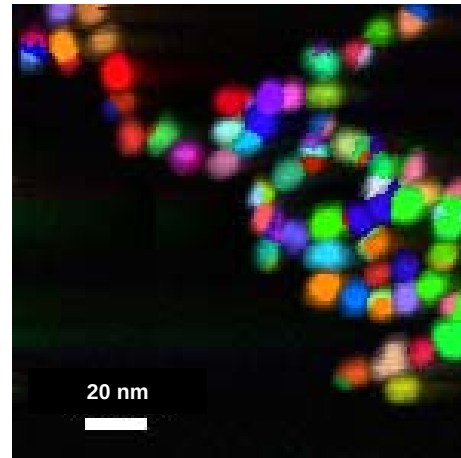
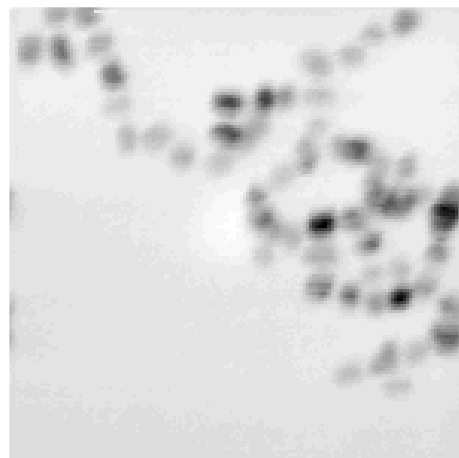


Orientation map



Correlation Index map

Pt nanocrystals



1) ACOM/TEM :

Template matching

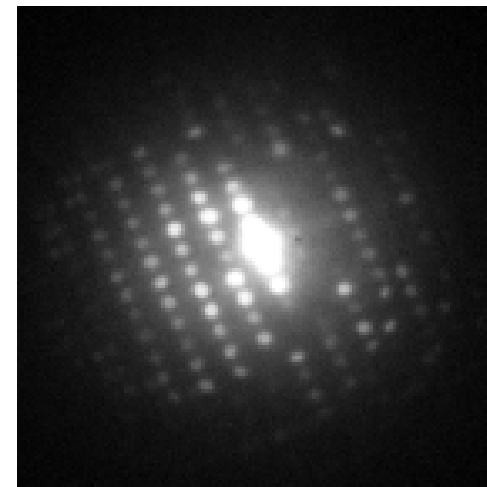
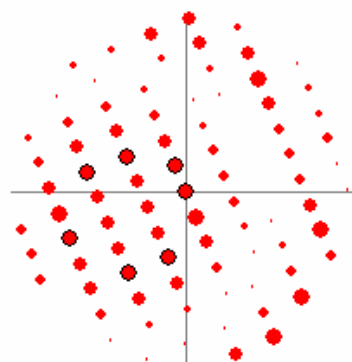
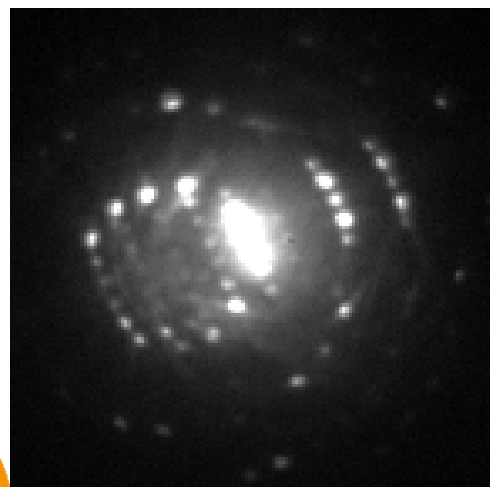
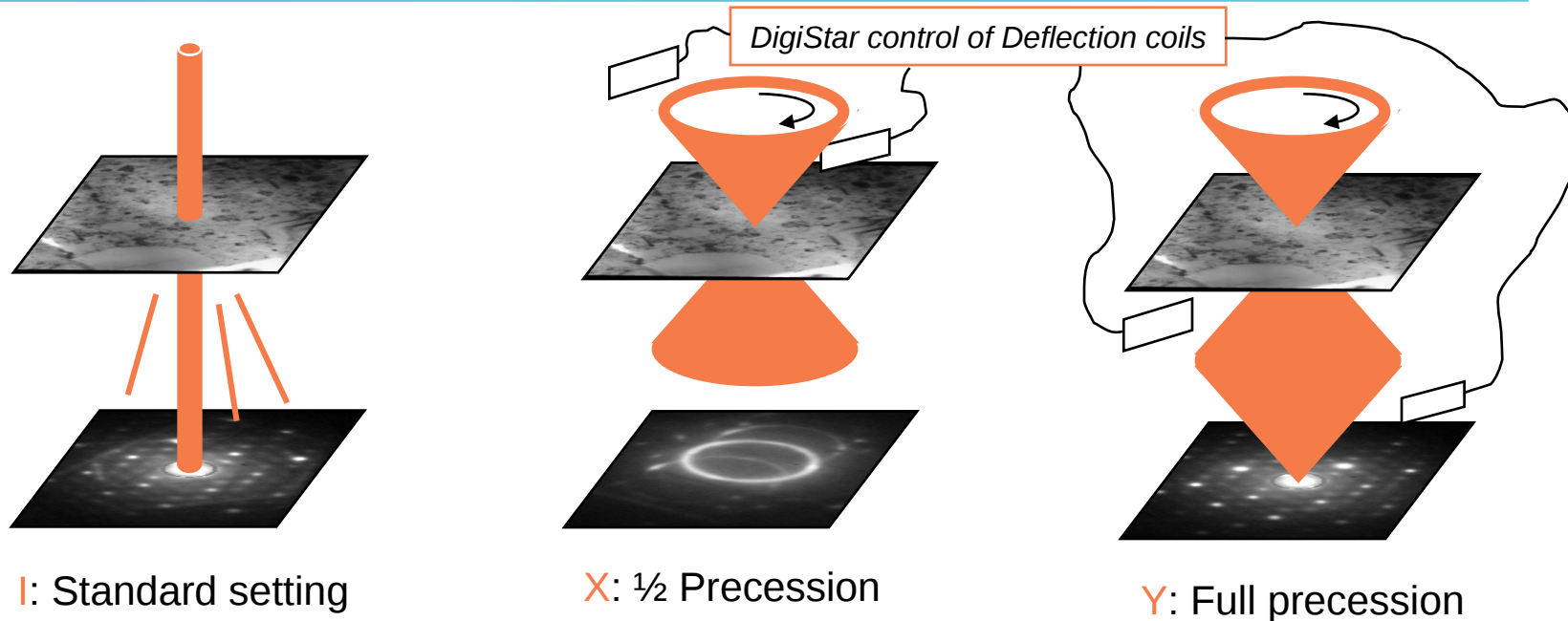
Pattern acquisition and template generation

2) ASTAR :

Combining orientation/phase identification
with Electron Precession

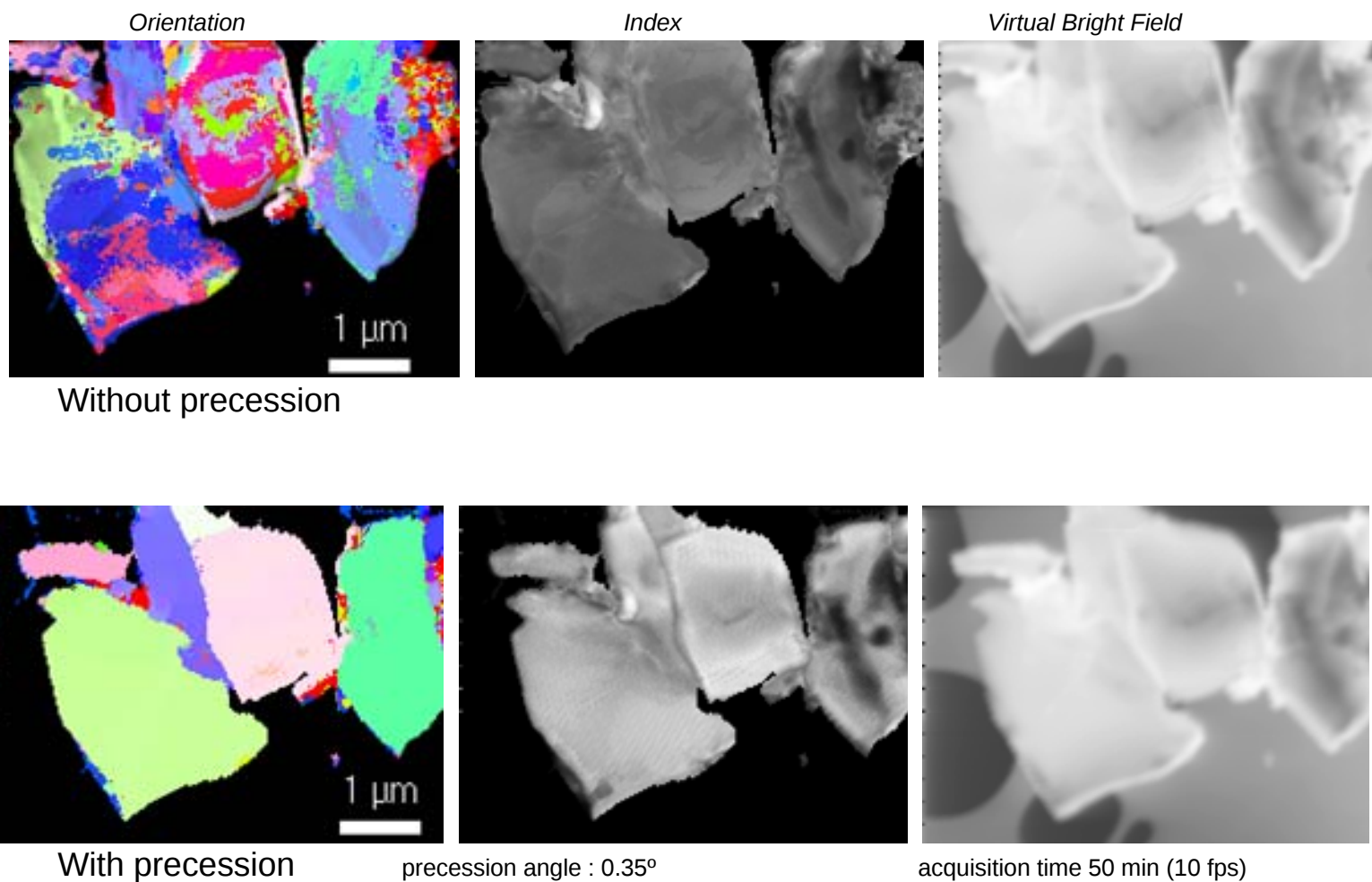
Precession Electron Diffraction patterns

(R. Vincent, P.A. Midgley, Ultramicroscopy 53 (1994) 271.)

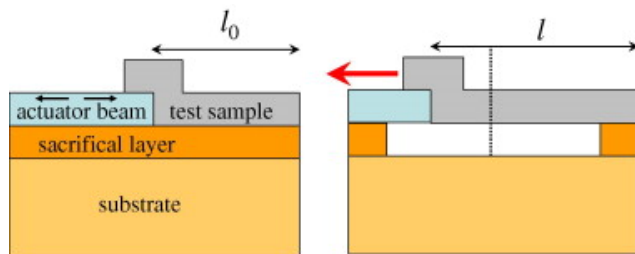


Precession Electron Diffraction patterns

Mayenite crystal ($\text{Ca}_{12}\text{Al}_{14}\text{O}_{33}$) : space group I-43d



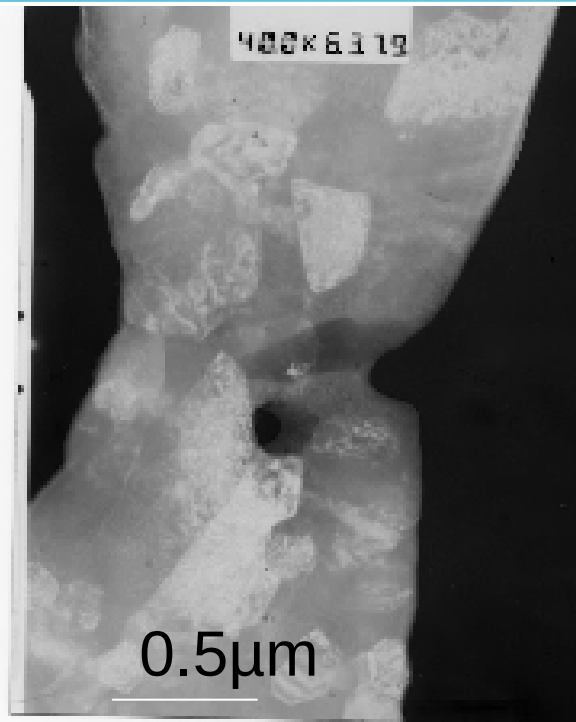
Deformation of Aluminum film



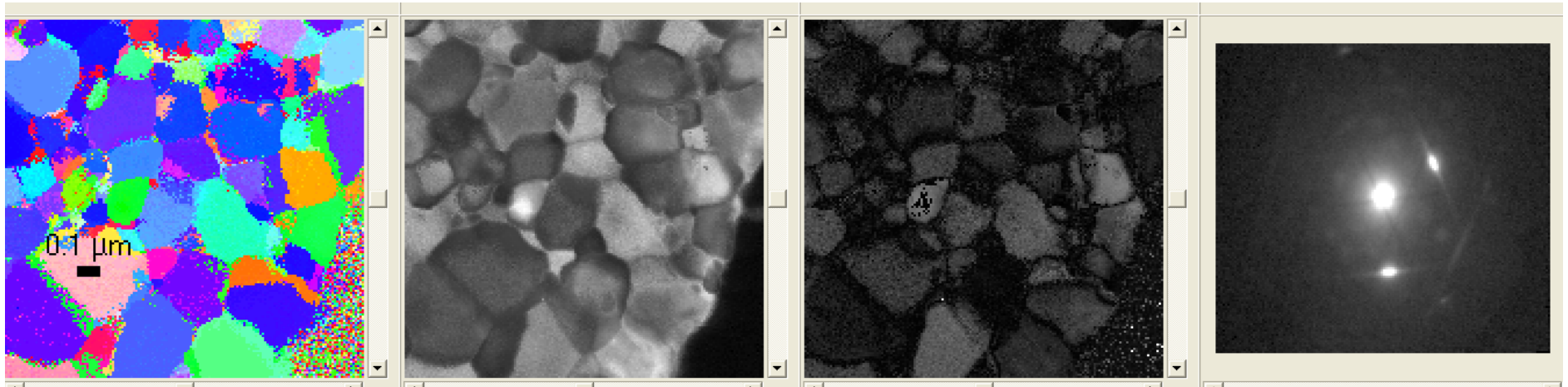
$$\epsilon^{mech} = \ln\left(1 + \frac{\Delta l}{l_0}\right) + (\alpha_{sub} - \alpha)\Delta T$$

$$\epsilon_{act}^{mech} = \ln\left(\frac{l_{0act} - \Delta l}{l_{0act} - \Delta l_{free}}\right)$$

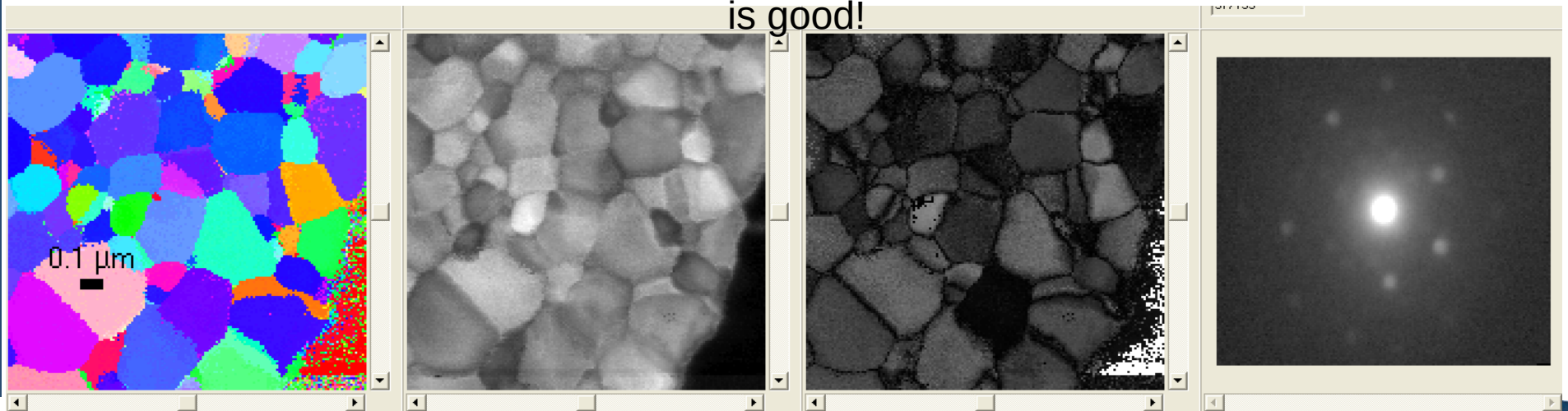
$$\sigma_{act} = E_{act} \epsilon_{act}^{mech} \quad \sigma = \sigma_{act} \frac{S_{act}}{S}$$



Good results were obtained with a precession angle $\alpha = 0.9^\circ$



Thick sample, same area, diffraction patterns with kikuchi lines. Without precession, quality is poor, with precession $\alpha = 0.9^\circ$, diffraction patterns are « cleaned », and indexing is good!

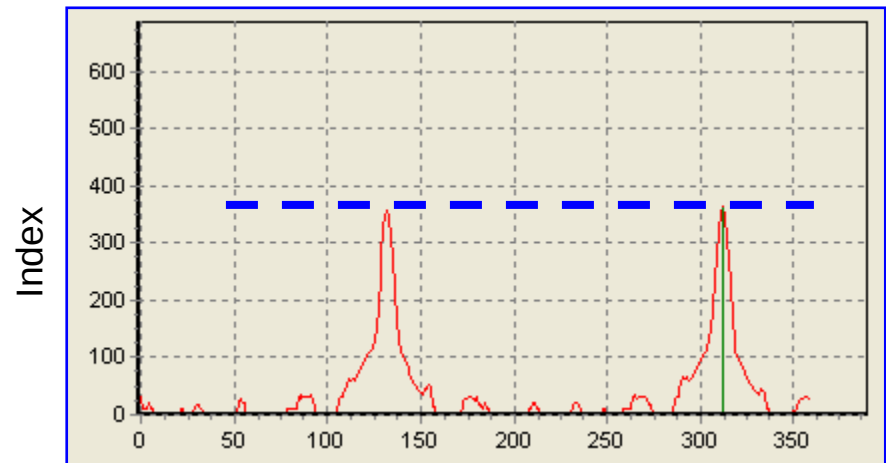
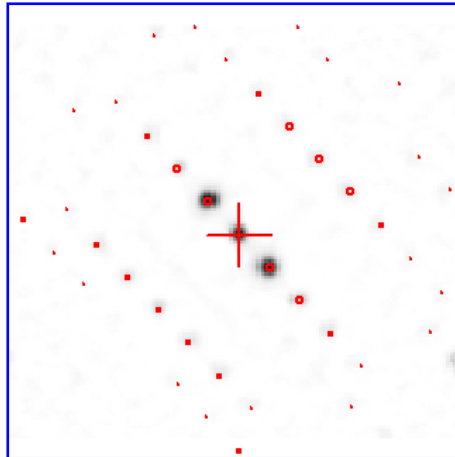
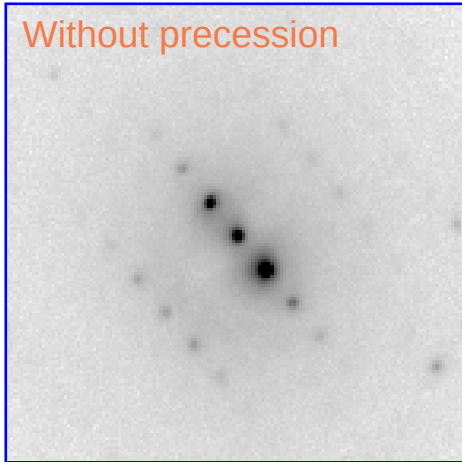


ACOM + Precession: Solving 180° orientation ambiguities

B.c.c. Iron (ferrite), [112]

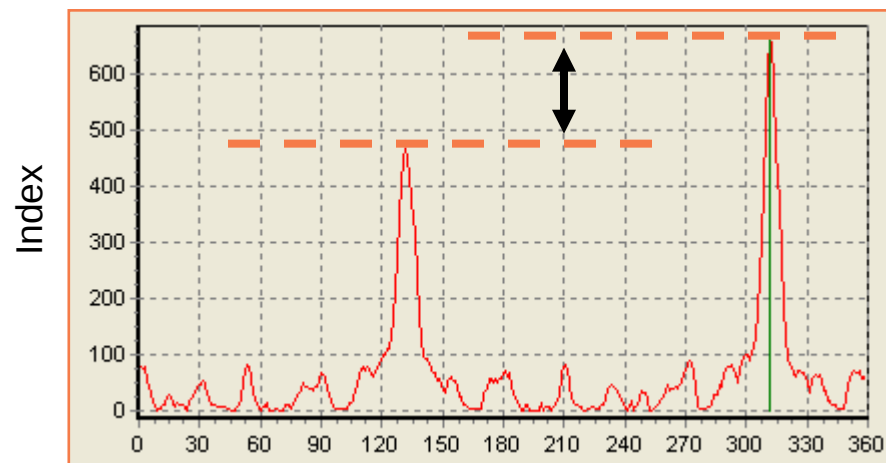
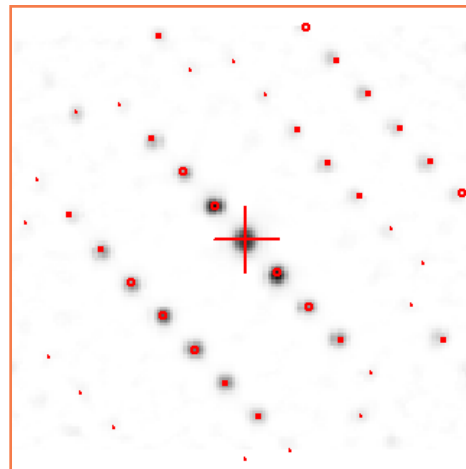
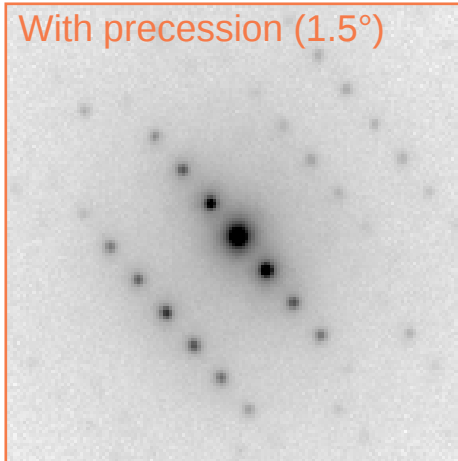
I : Index=317, Reliability=0

Without precession



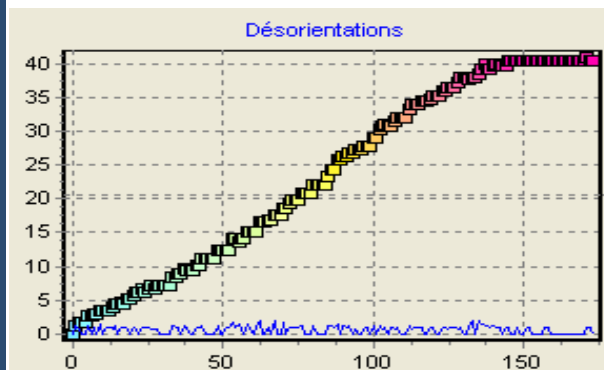
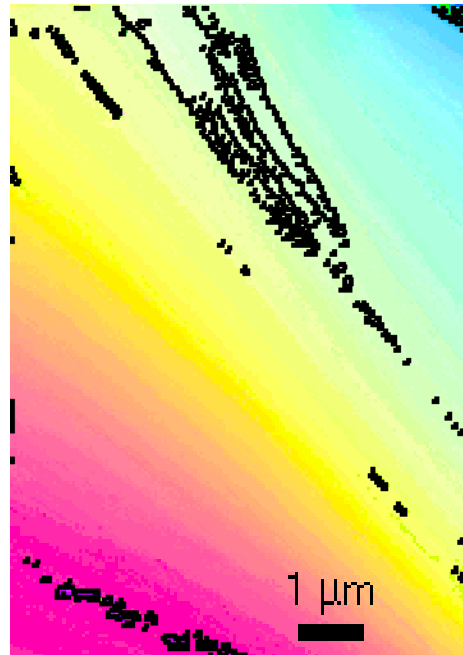
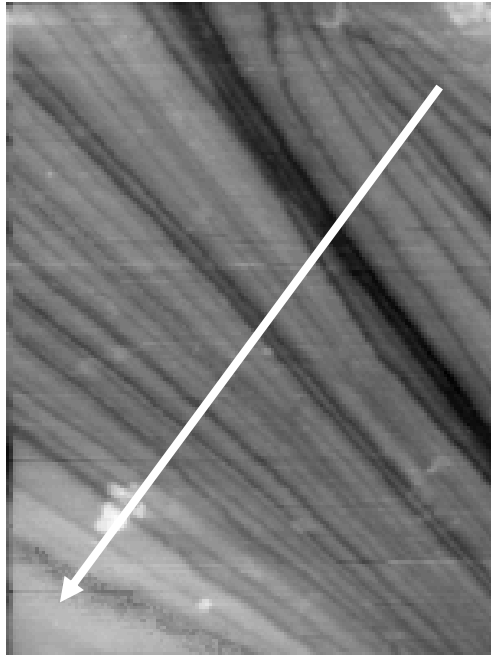
Rotation angle (around the normal axis)

With precession (1.5°)



Y : Index=670, Reliability=28

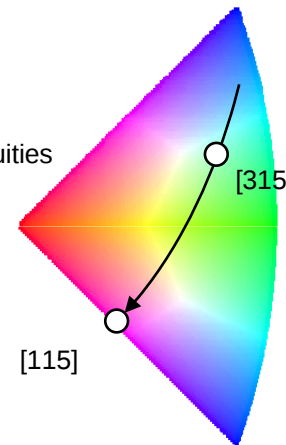
ACOM + Precession: Solving 180° orientation ambiguities



Fe-1.5%Cu (annealed)

Precession angle 0.5°

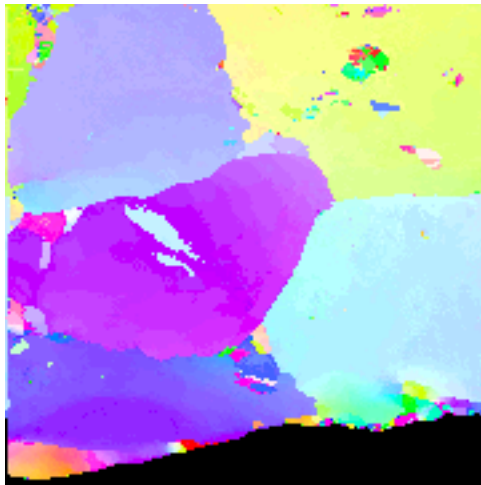
Orientation ambiguities



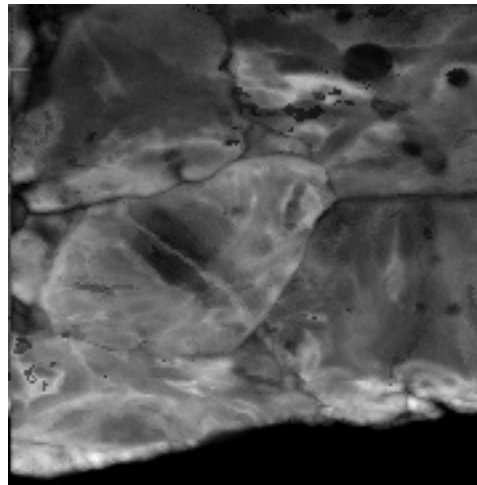
■ DiffGen : Template generator

Same area with (Y) and without (I) precession

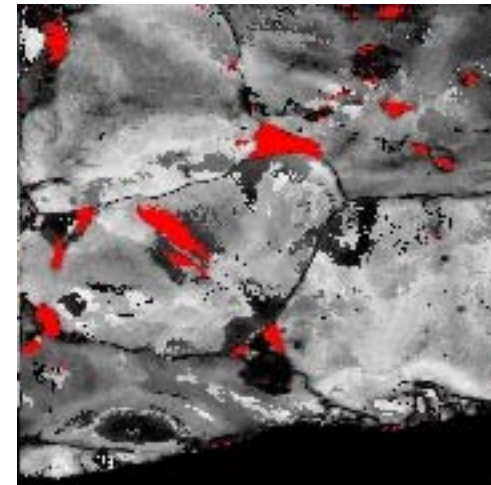
TRIP steel (ferrite + austenite) ; Philips CM120 @ 100hz (6 min),



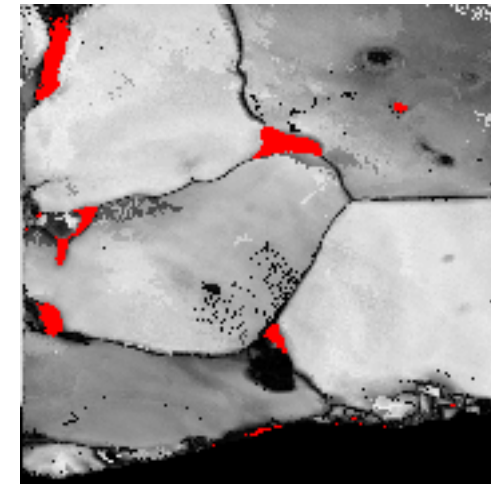
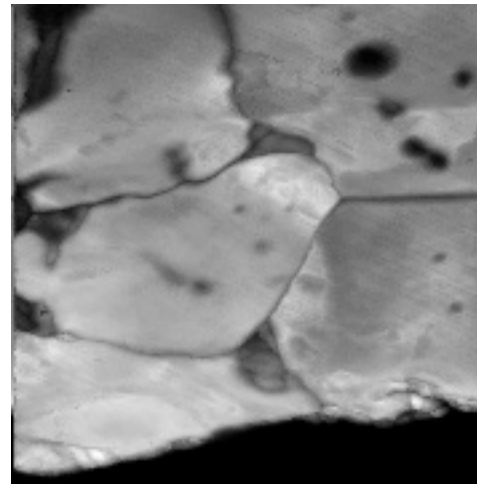
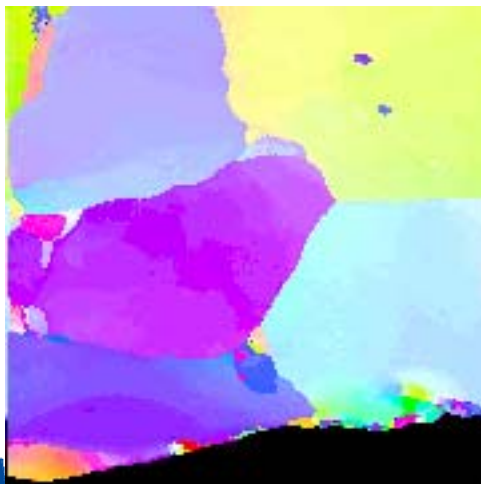
Orientation



Index



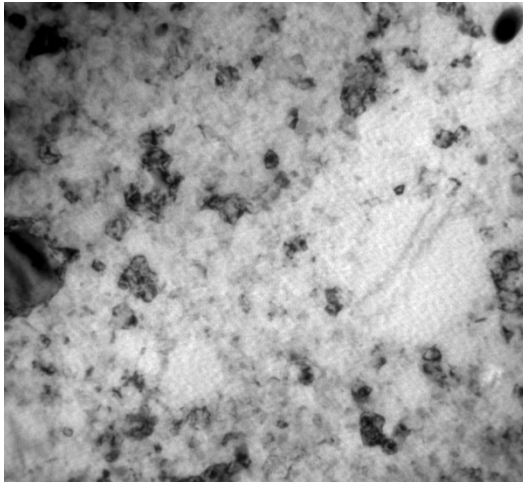
reliability +phase



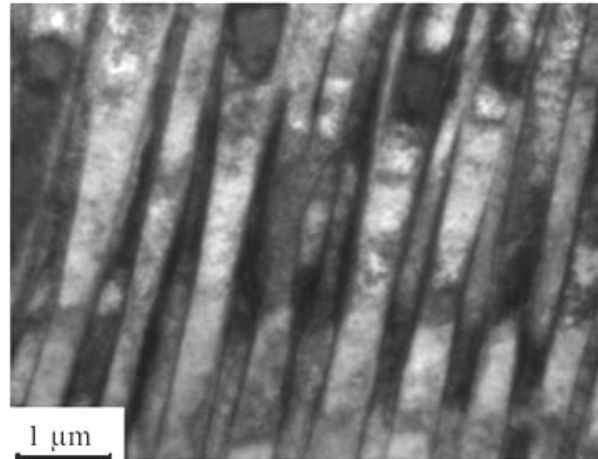
INDEX : pattern identification software

ACOM : some examples of orientation maps

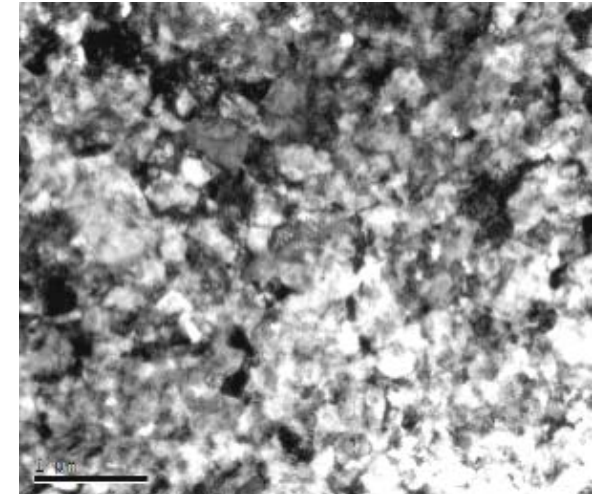
Bright field images



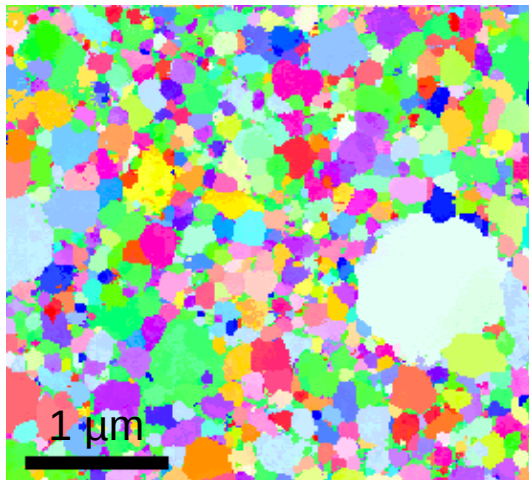
Nanocrystalline Al



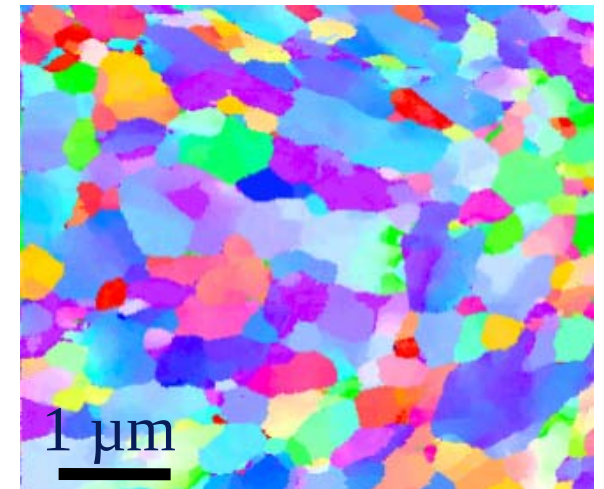
Deformed steel



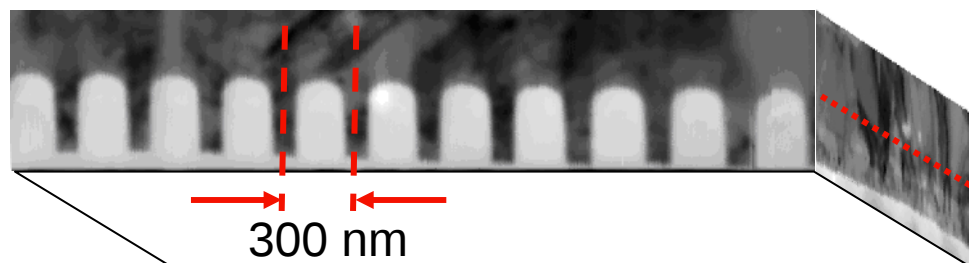
Severely deformed Cu



Orientation maps



Grain size and Texture in 80 nm copper lines



500x100 steps (6.5 nm each) , Spot size 25 nm
Scanning time : 19 min (44 fps)

Side view



300x100 steps (6.5 nm each), spot size 15 nm
Scanning time : 12 min (44 fps)

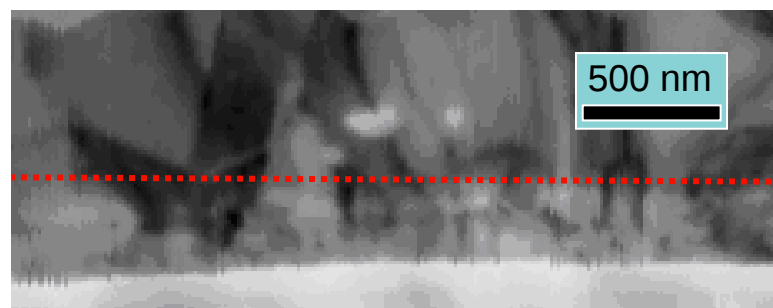
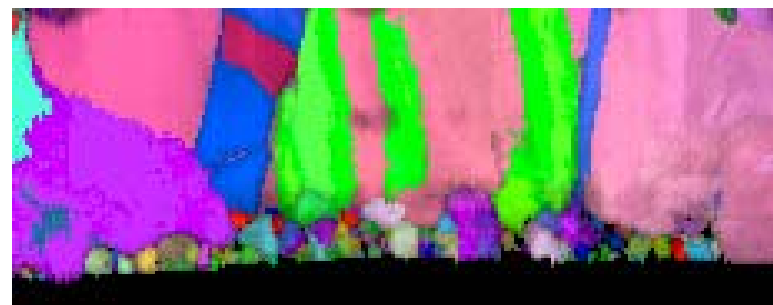


SIDE VIEW (orientation and index superimposed map)
The two scans were performed with different settings
They demonstrated the reproducibility of the identification

CROSS VIEW (orientation map)

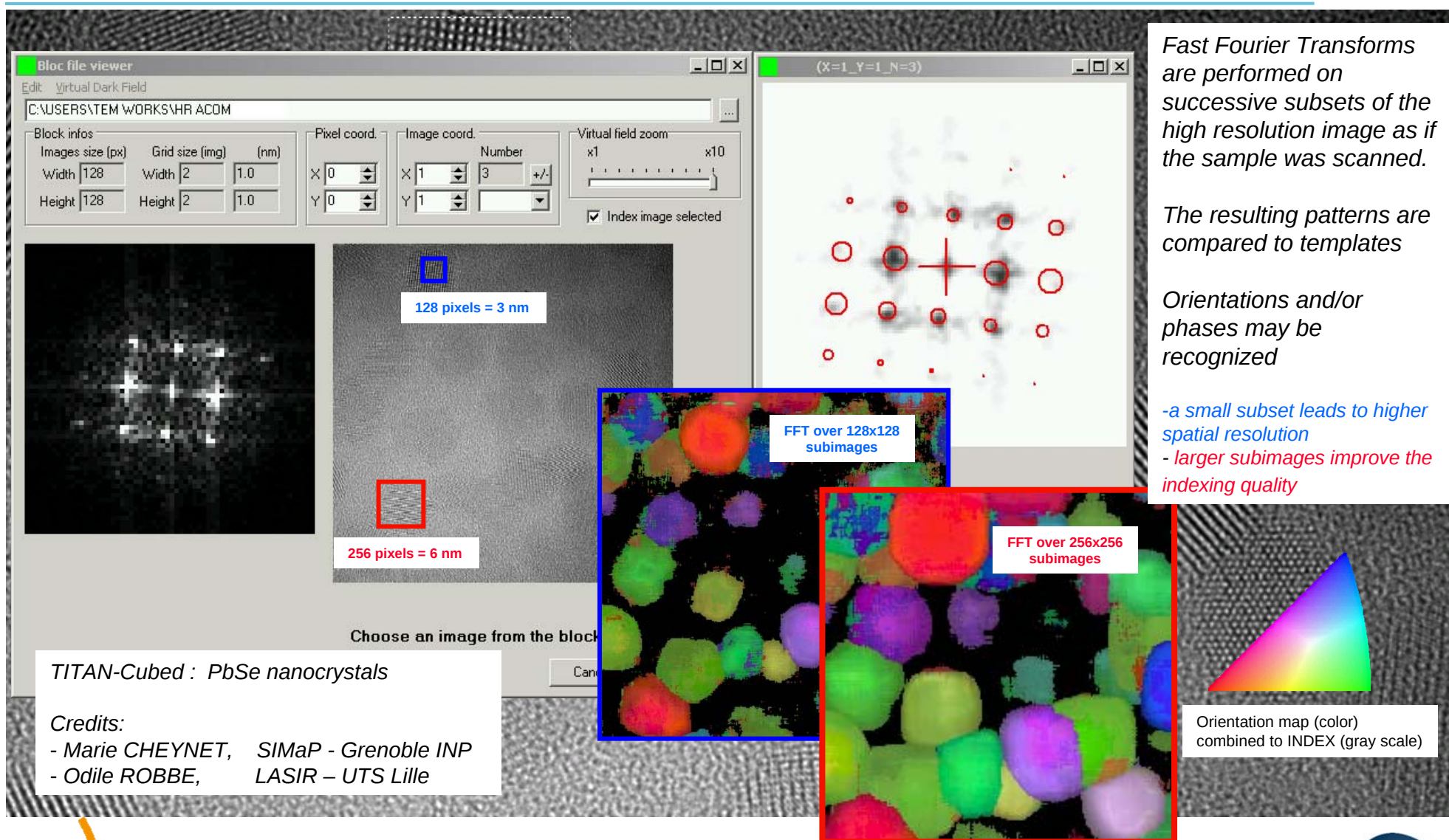
Grain size of the order of 30 nm may be identify despite the use of a conventional LaB6 equipped Jeol 3010 TEM (spot size 25 nm).
A fiber texture was detected within the channel.

250x100 steps (13 nm each)
LaB6 equipped Jeol 3010 TEM (spot size 25 nm)
Scanning time : 10 min (44 fps)



Credits:
- Stefan BRANDSTETTER, SIMaP - Grenoble INP

Indexing Fourier transform of High resolution TEM images



Fast Fourier Transforms are performed on successive subsets of the high resolution image as if the sample was scanned.

The resulting patterns are compared to templates

Orientations and/or phases may be recognized

- a small subset leads to higher spatial resolution
- larger subimages improve the indexing quality

TITAN-Cubed : PbSe nanocrystals

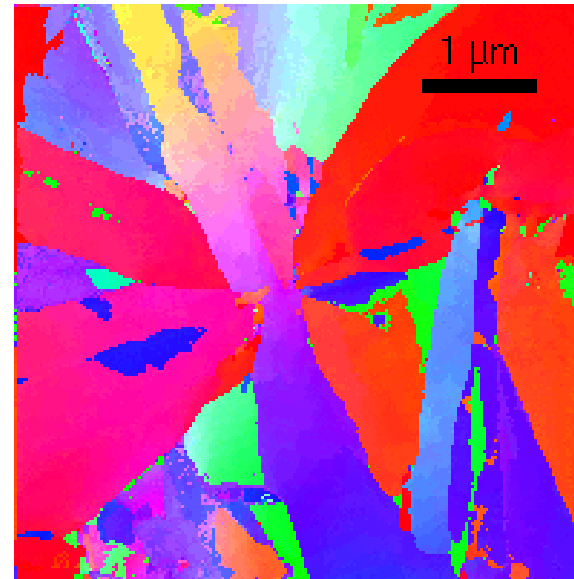
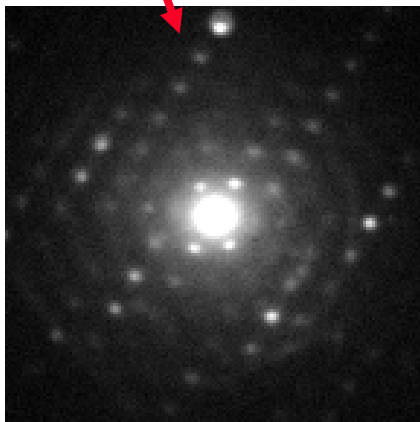
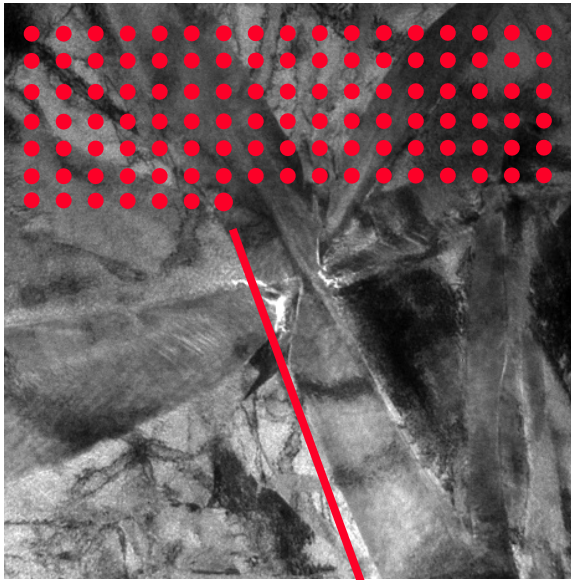
Credits:

- Marie CHEYNET, SIMaP - Grenoble INP
- Odile ROBBE, LASIR – UTS Lille

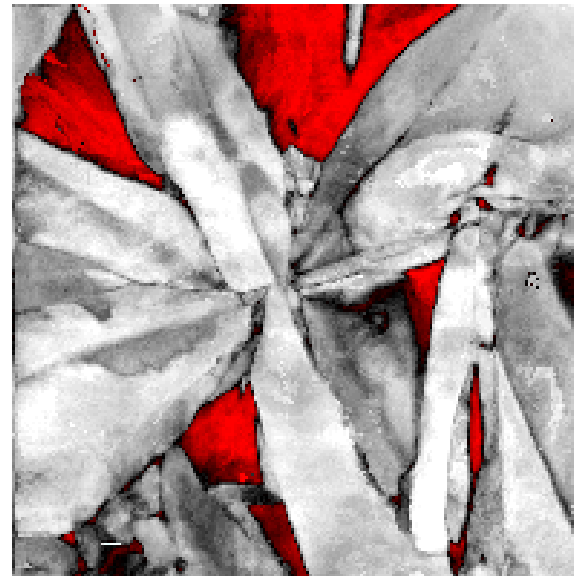
Orientation map (color) combined to INDEX (gray scale)

ACOM/TEM : Automated Crystal Orientation Mapping

Fe 1.67% C (HT 10 min @ 1100°C, A. Stormvinter - KTH)



Orientation map



Phase map

Austenite
Martensite

ACOM : orientation and phase maps

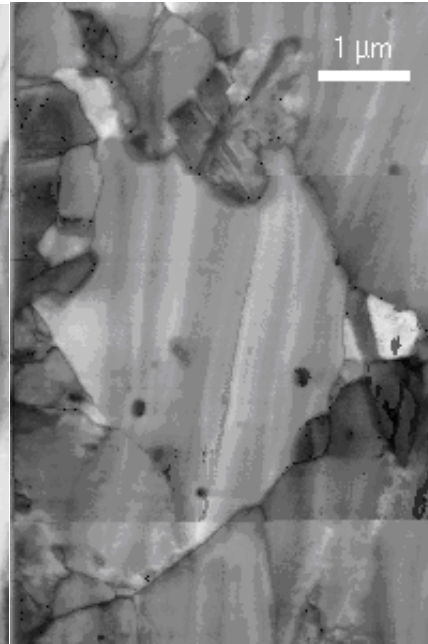
TRIP steel with retained austenite



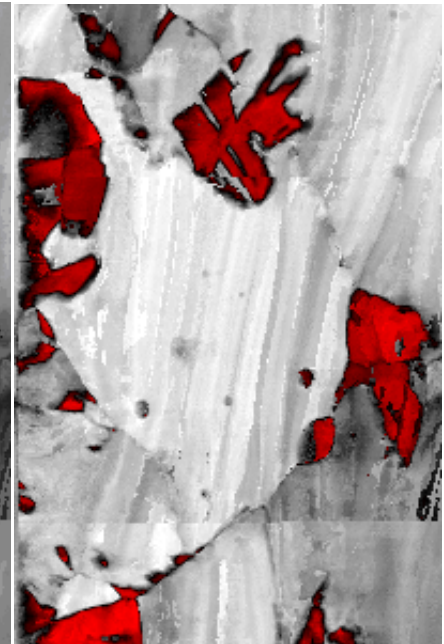
Orientation maps



Virtual bright field



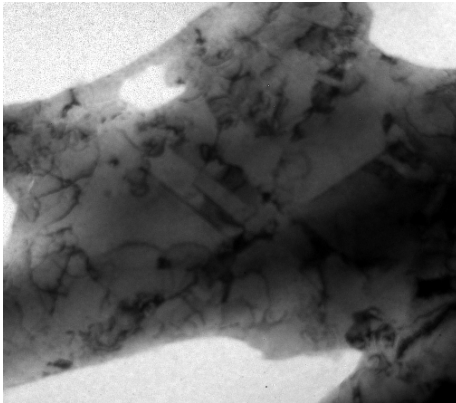
Correlation Index



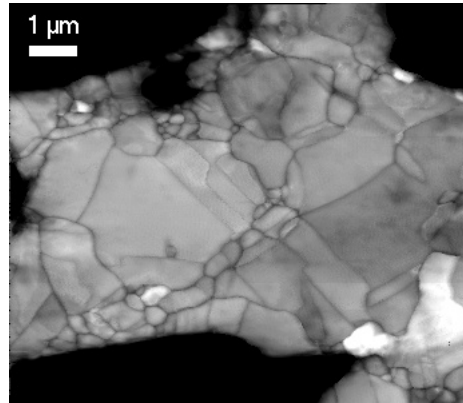
Phase + reliability

ACOM : some examples of orientation maps

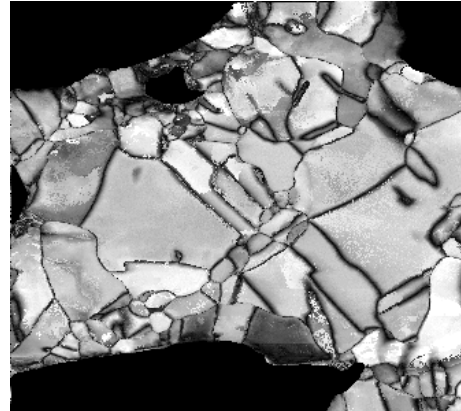
Deformed Cu (coll. N. Llorca – Univ. Barcelona, Spain)



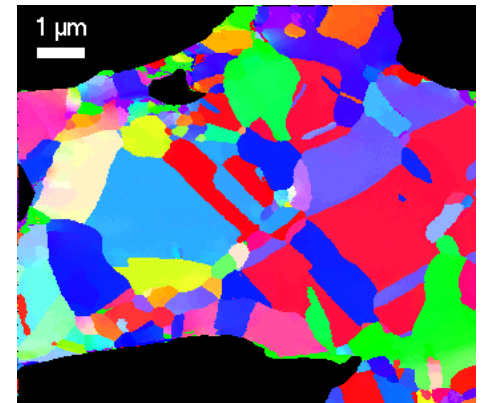
Bright field



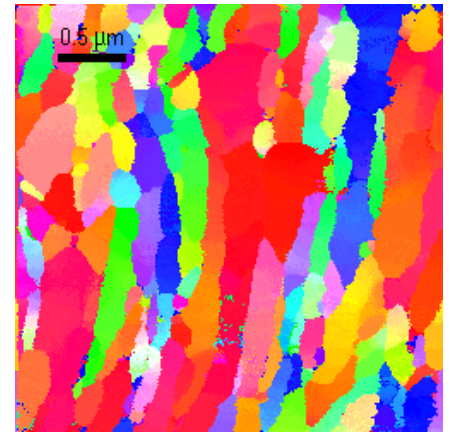
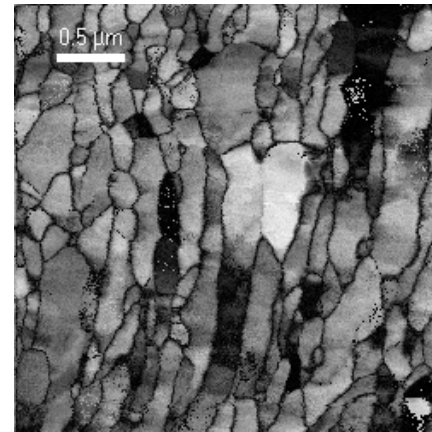
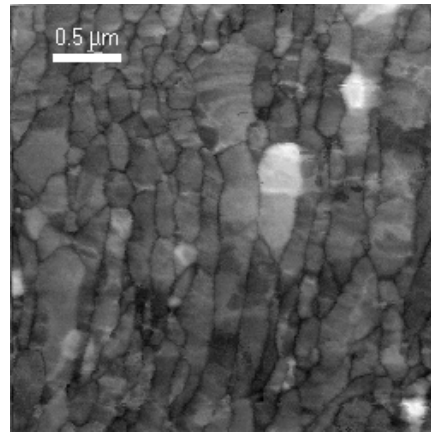
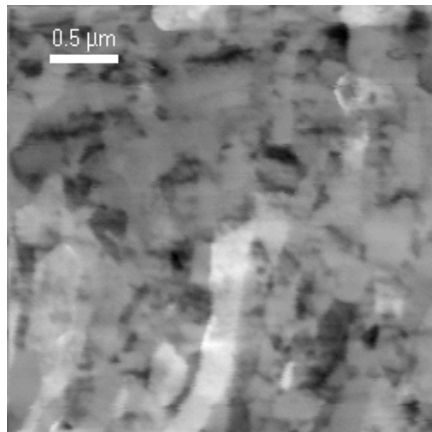
Correlation Index



Reliability



Orientations

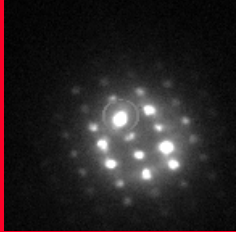


Severely Deformed Fe (coll. S. Descartes – LaMCoS, Lyon - France)

5				9	2	6		
	4	7						
			1				4	5
4			7	1		9		
8	3				4		1	
	8	9						
				6		2		
		2		8		7		

ACOM/TEM : four steps

TEMdpa.exe

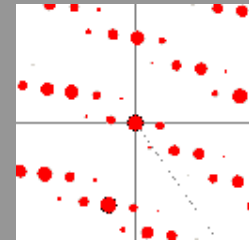


On line
(hardware)

INDEX.exe

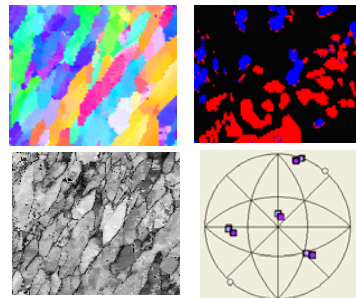
$$Q(i) = \frac{\sum_{j=1}^m P(x_j, y_j) T_i(x_j, y_j)}{\sqrt{\sum_{j=1}^m P^2(x_j, y_j)} \sqrt{\sum_{j=1}^m T_i^2(x_j, y_j)}}$$

DiffGen.exe

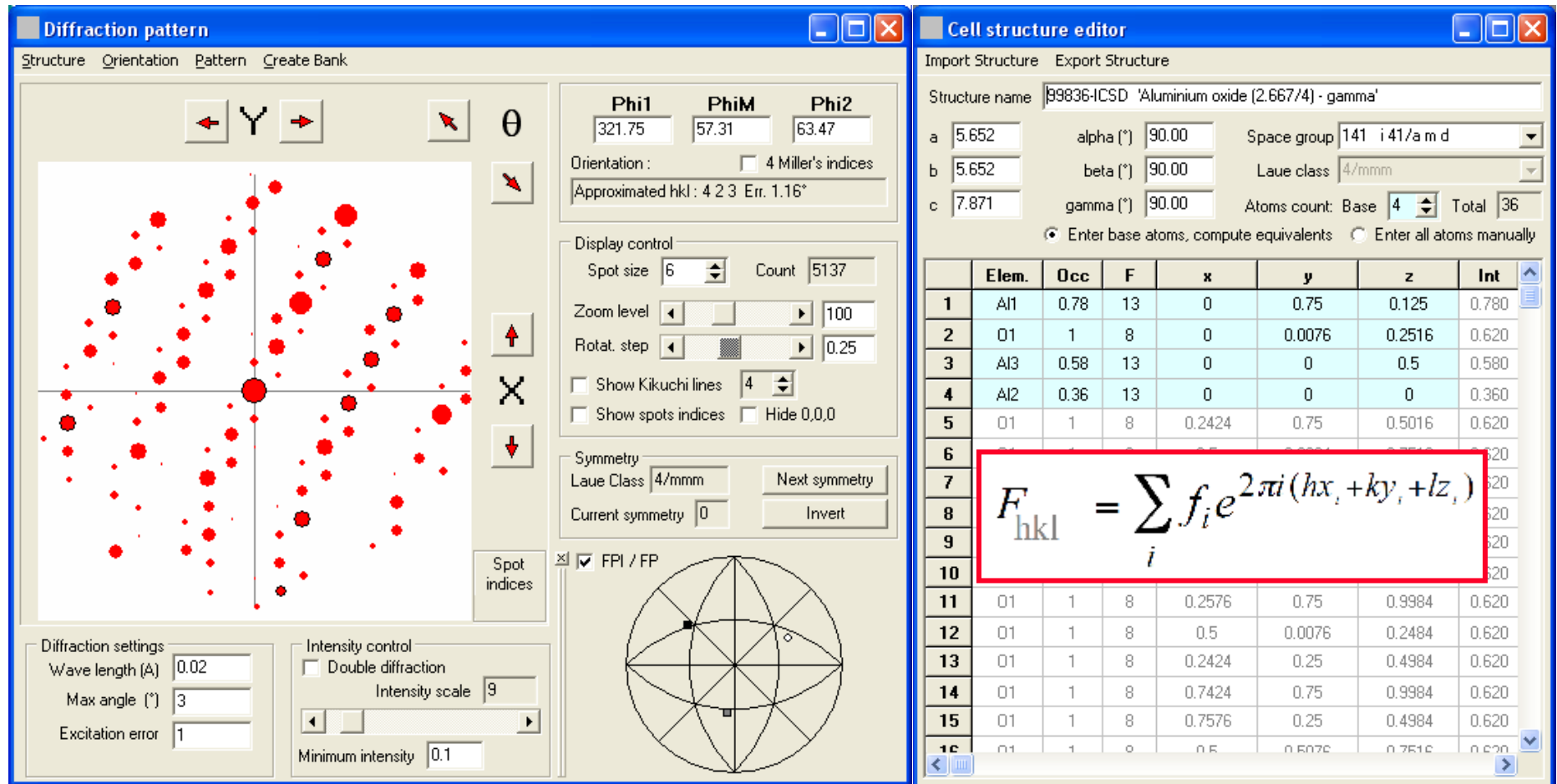


Off line

MapView.exe



DiffGen : Template generator

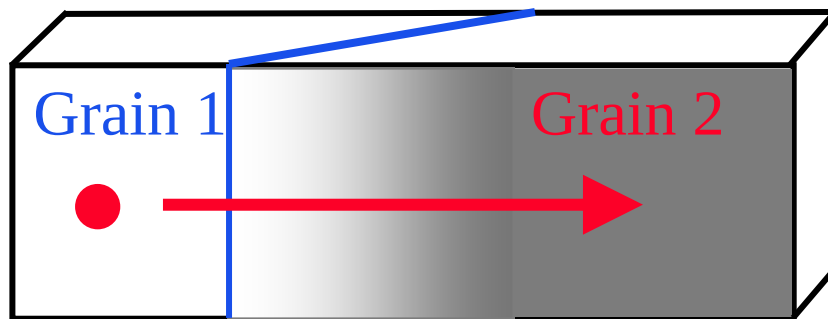
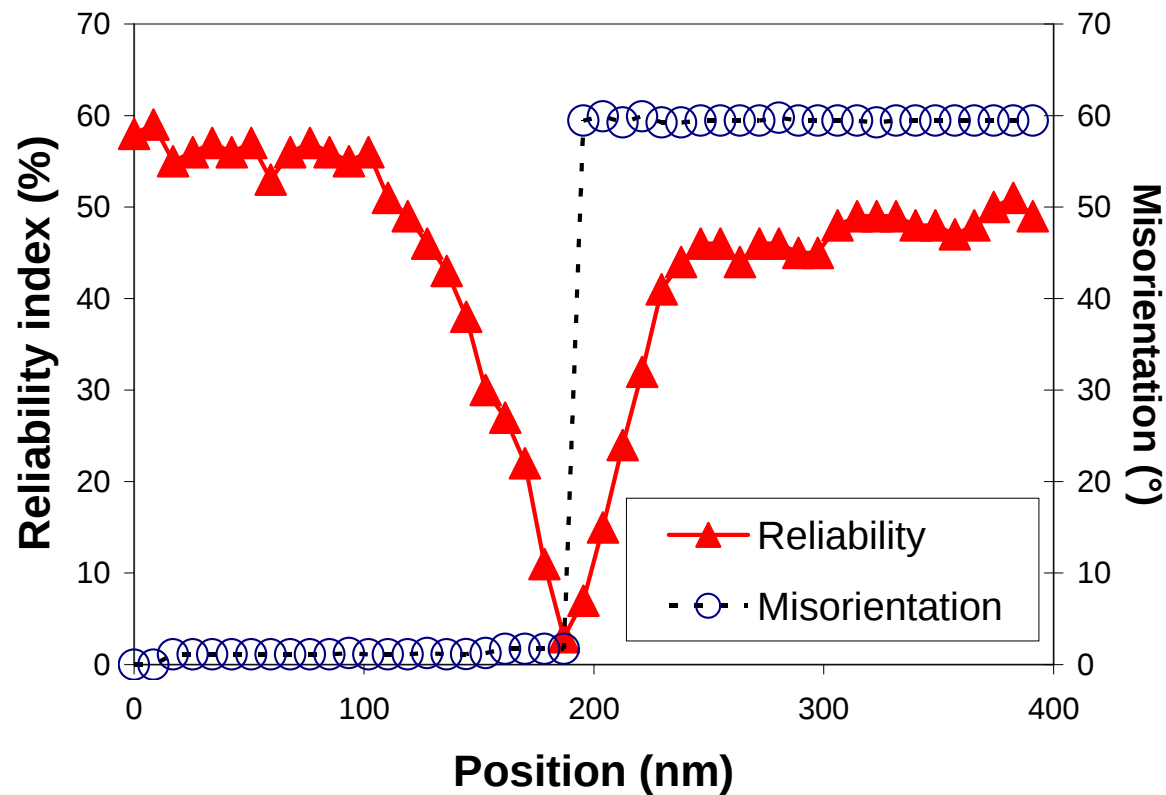


Features: Any crystallographic structure, any orientation

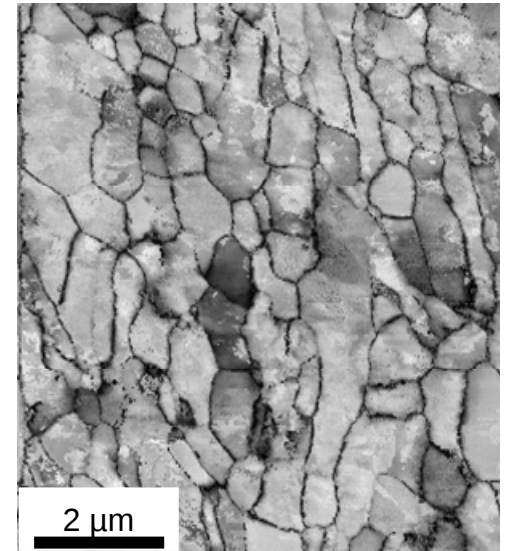
Laue class related to the space group

Structure generator (lattice, cell, structure factor)

Deconvolution of superimposed Diffraction patterns



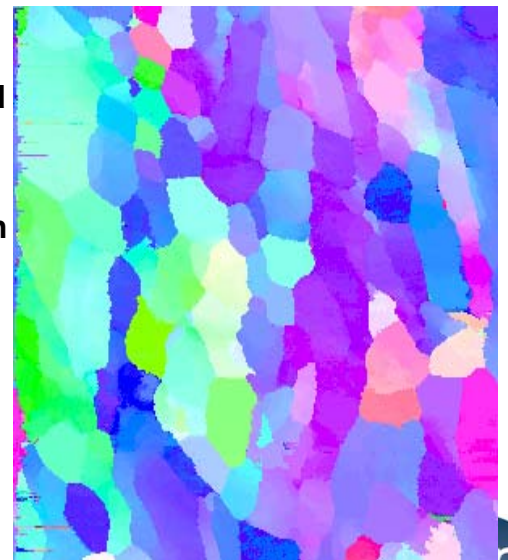
reliability



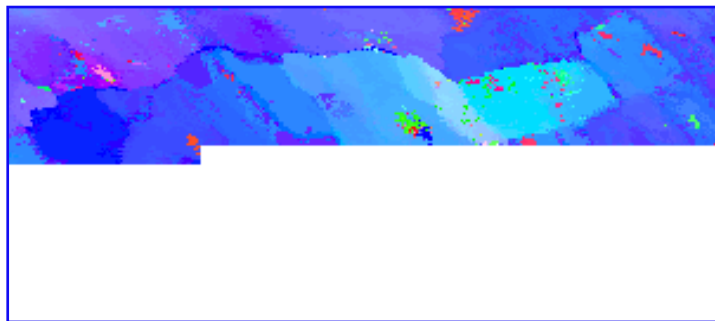
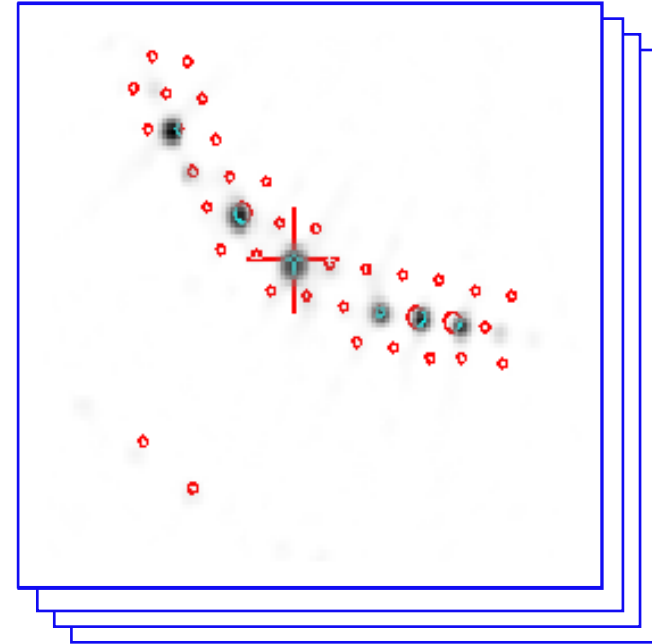
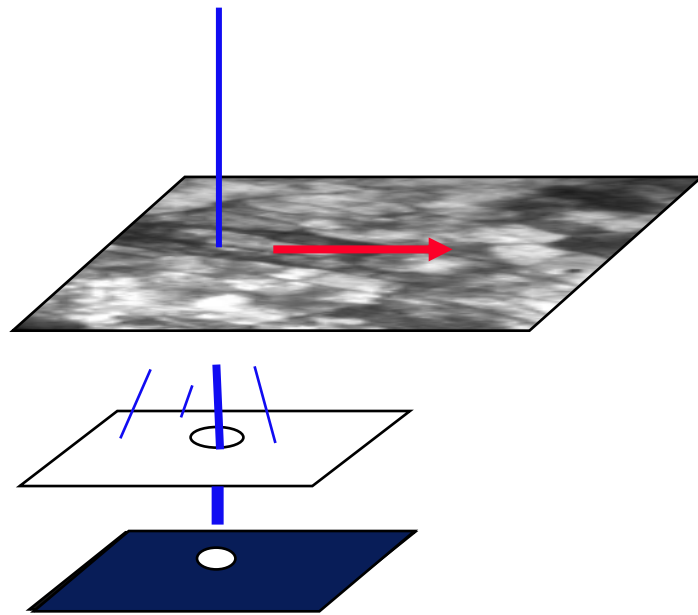
Fe - 60 ppmC severely deformed

Bright field

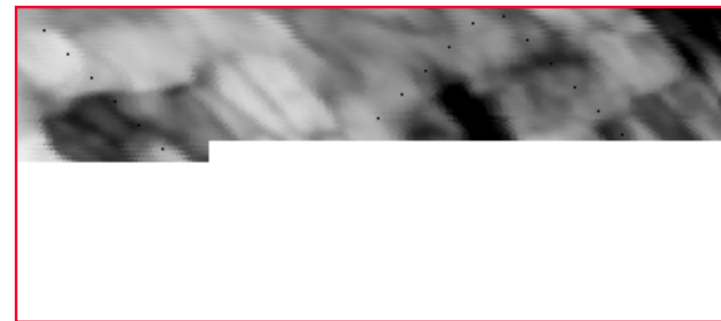
Orientation map



TEMdpa : Virtual Bright Field on-line construction

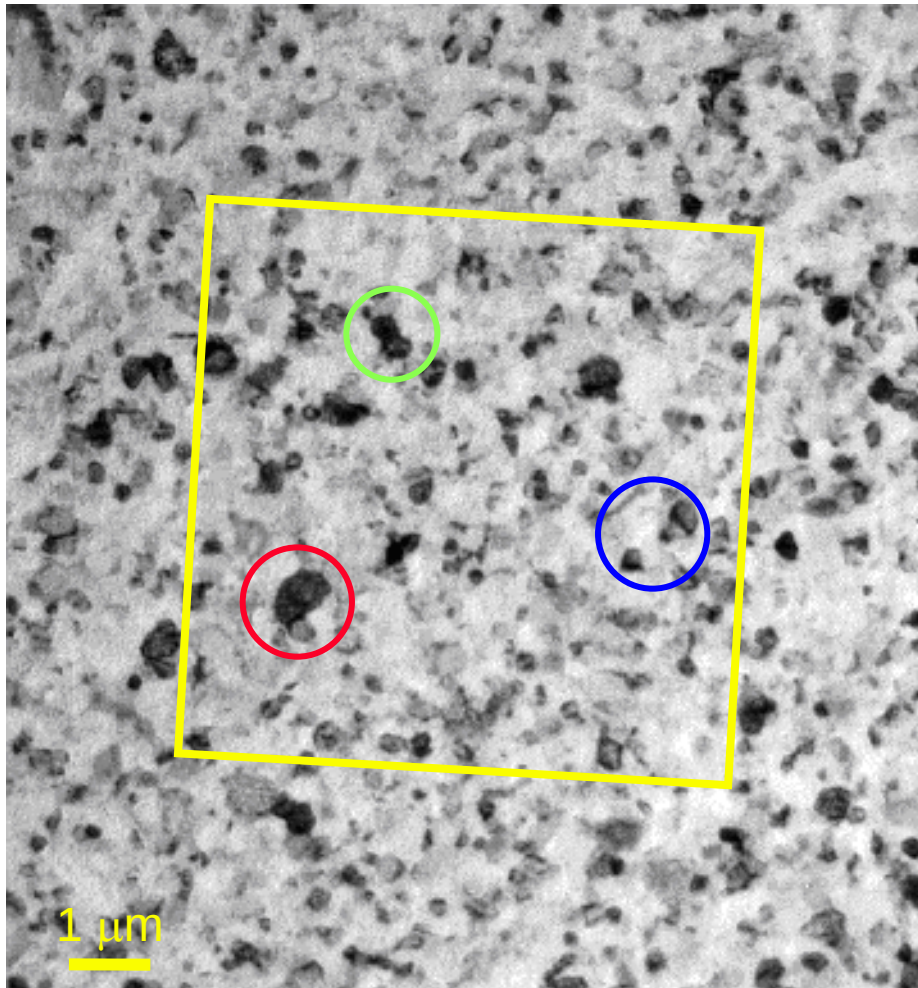


Orientation map

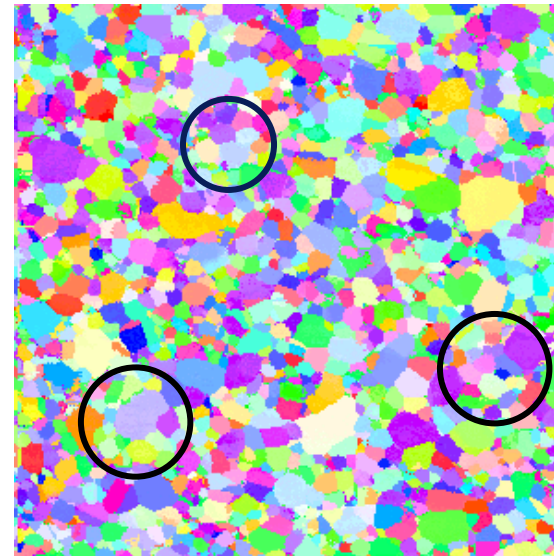


‘ Bright field ‘

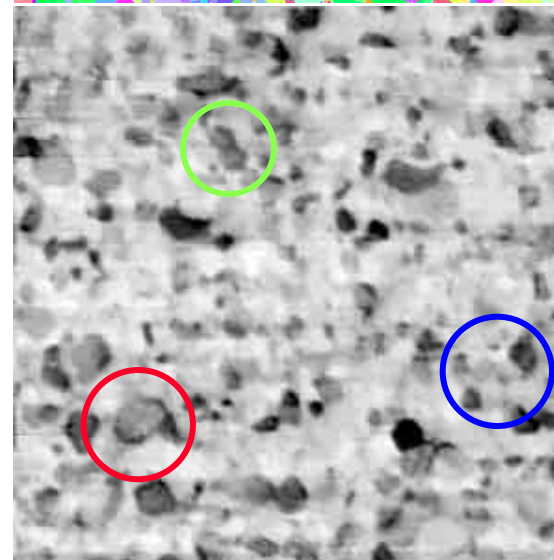
TEMdpa : Virtual Bright Field on-line construction



Bright field image



Orientation map



Virtual bright field image

Aluminium (mean grain size 200nm)